

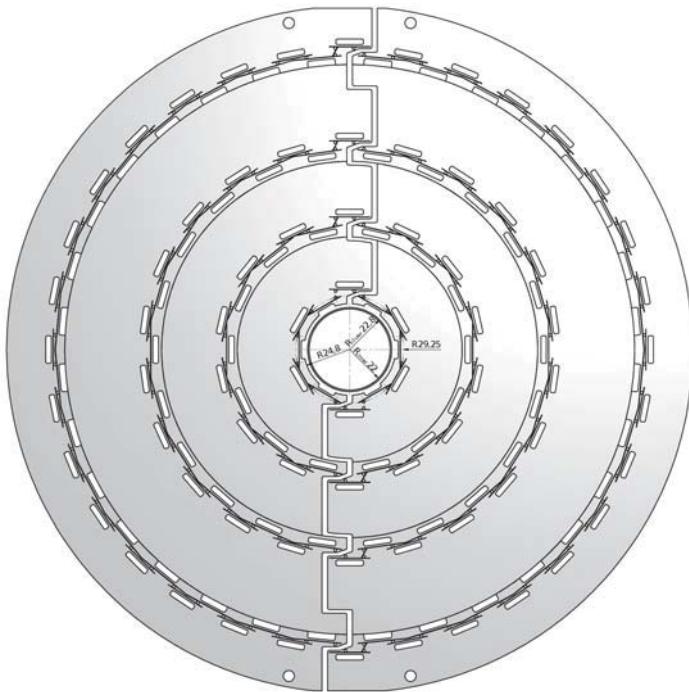


HELMHOLTZ
ASSOCIATION

CMS Pixel Detector Upgrade

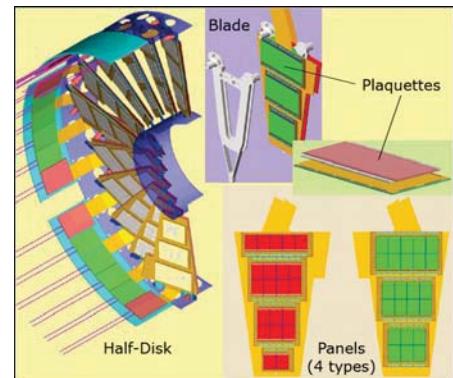
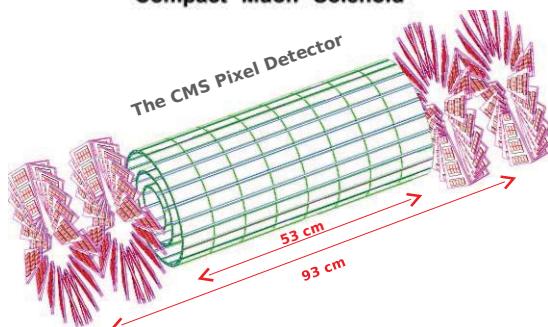
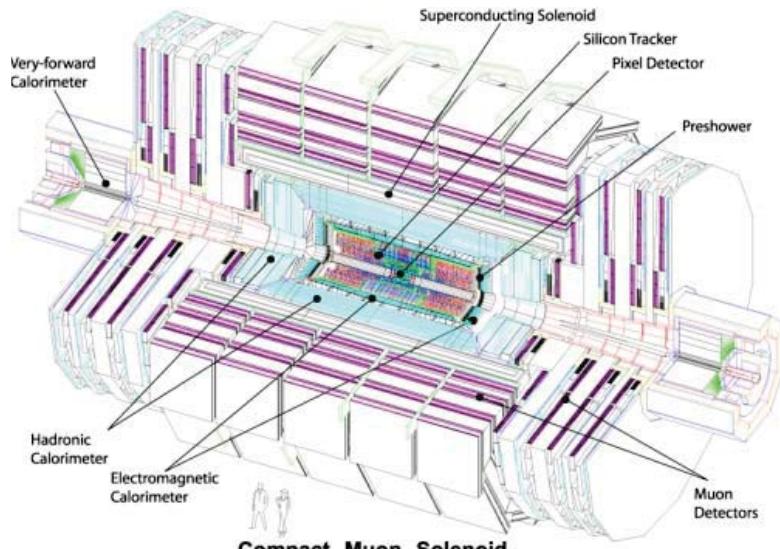


Daniel Pitzl, DESY
DESY Technisches Seminar 22.11.2011



- Present pixel detector
- 4-layer upgrade
- Read out chip modifications
- Module assembly, testing, and calibration
- preparations at DESY and Uni Hamburg

CMS and its pixel detectors



Panels of the Forward Pixel Detector

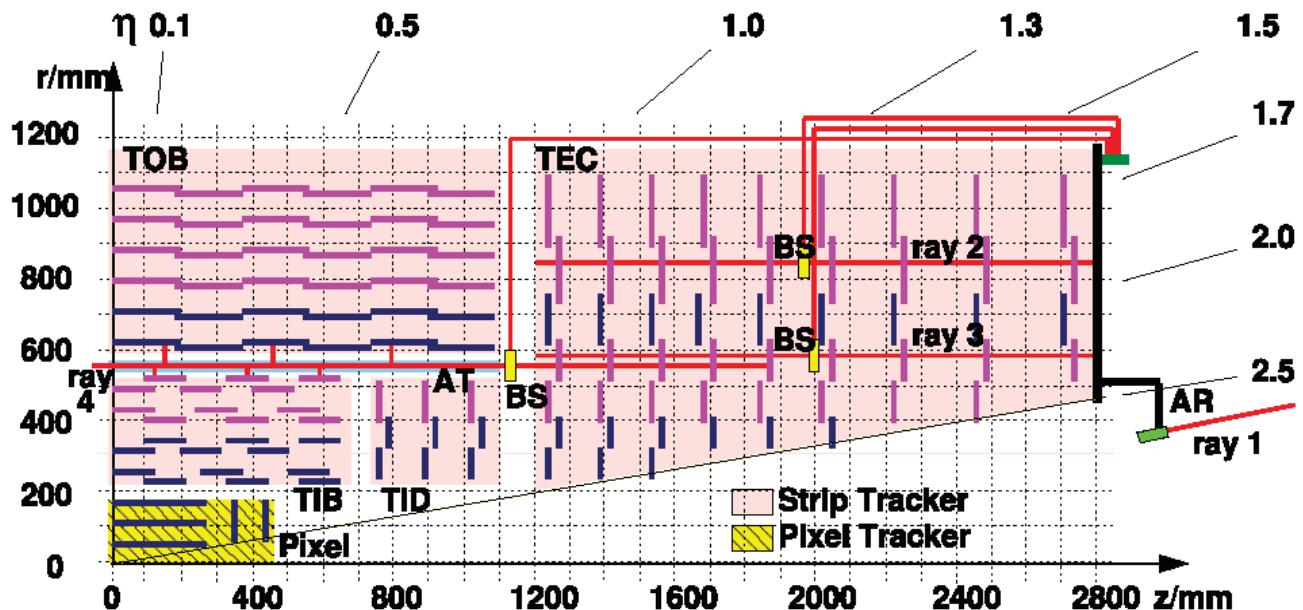
Forward Pixel Detector has 2 disks on each side at $z = 34.5 \text{ cm}$ and 46.5 cm . FPix has 672 modules.



Barrel Pixel Detector has 3 layers at $R = 4.4 \text{ cm}$, 7.3 cm , and 10.2 cm . BPix has 768 modules.

Total of $\sim 15,840$ readout chips, 66M pixels.

CMS Si Tracker

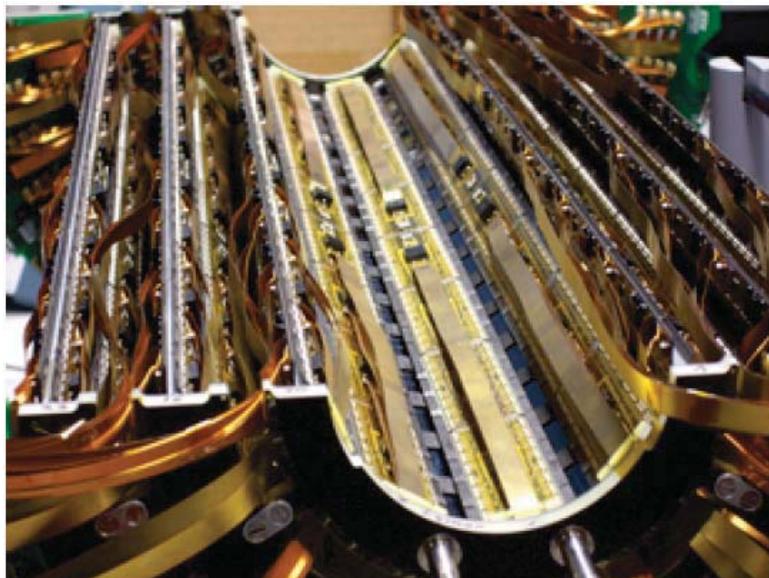


D. Pitzl (DESY): CMS Pixel Upgrade

3

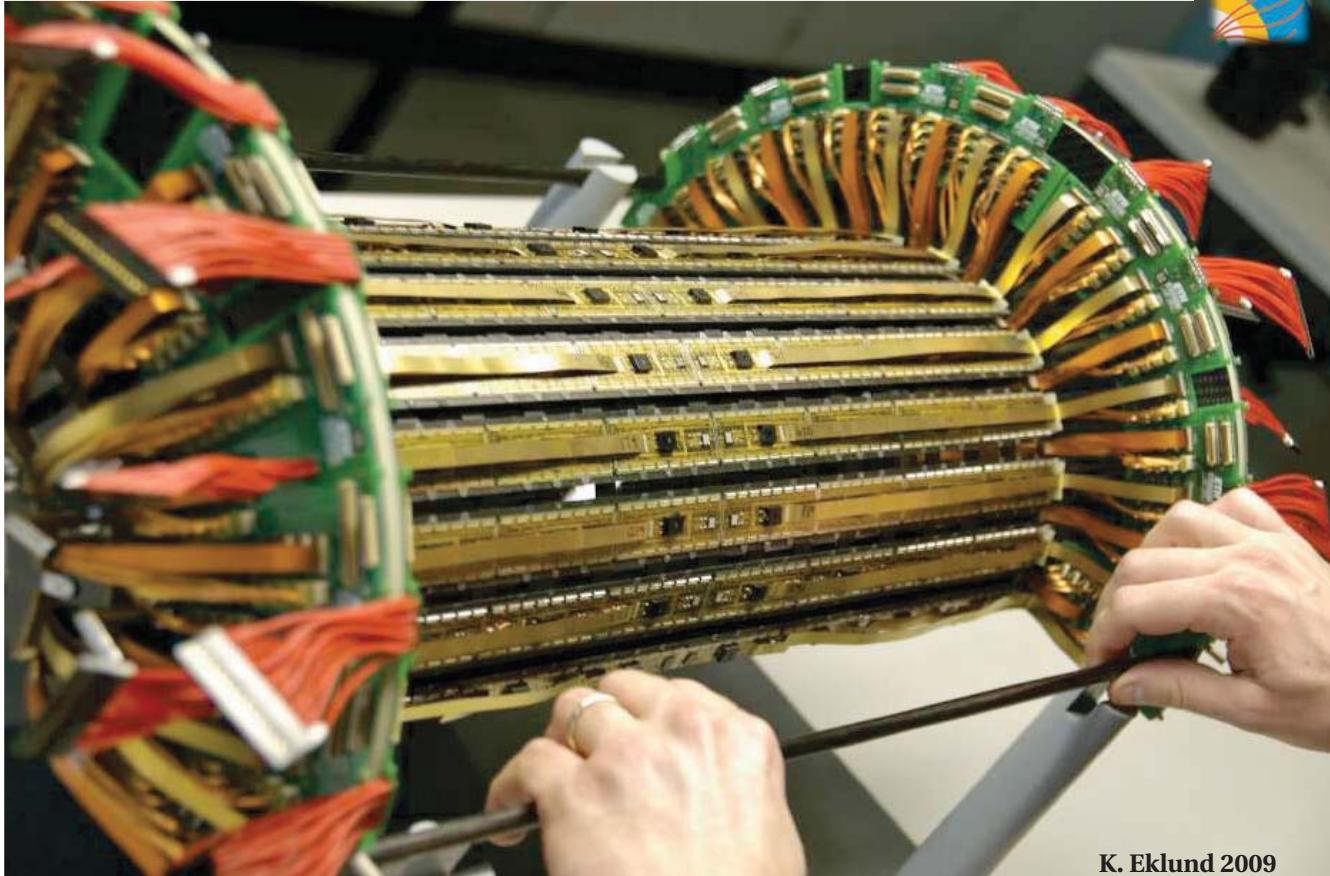
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CMS at present: 3 barrel pixel layers



- Developed and built at PSI, CH, 1994 - 2008.
- Active length 52 cm.
- 3 layers:
 - $\langle R \rangle = 4.4, 7.3, 10.2 \text{ cm}$
- 768 modules
- 12'000 chips
- 51M pixels
- 1.5 kW
- 5.2 kg

Present barrel pixel detector



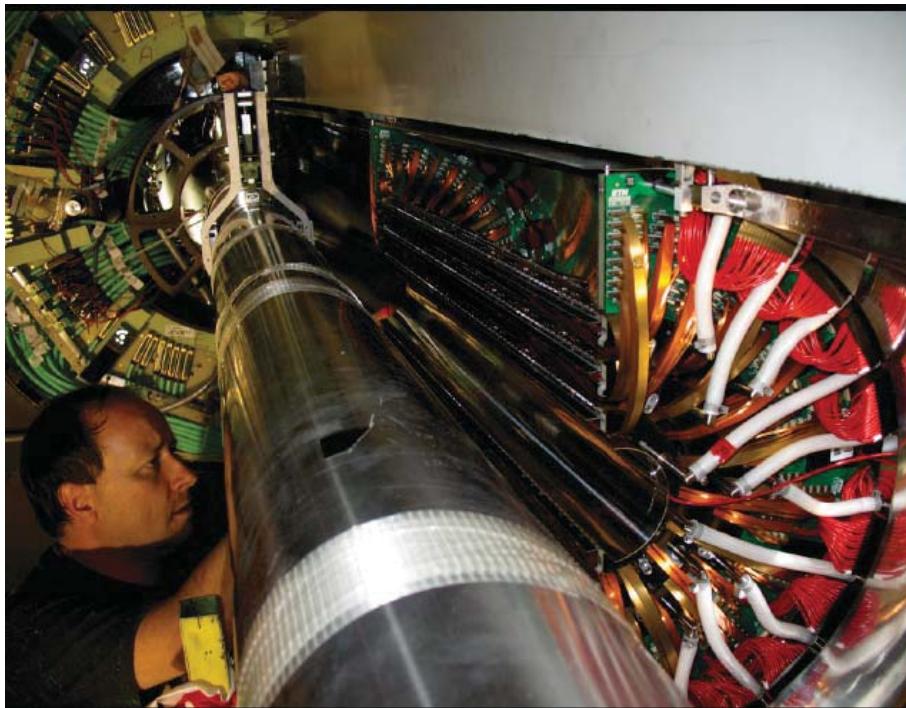
K. Eklund 2009

D. Pitzl (DESY): CMS Pixel Upgrade

5

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Barrel Pixel insertion 2008



- The CMS pixel detector is accessible and removable during extended Christmas maintenance.
- Removal required for beam pipe bake out (vacuum conditioning).
- There is space for a 4th barrel layer.

Conical beam pipe: smaller at the IP.

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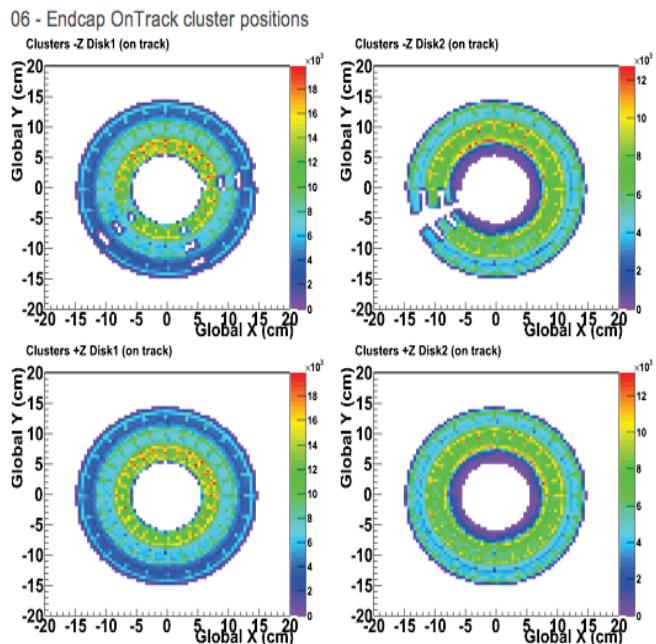
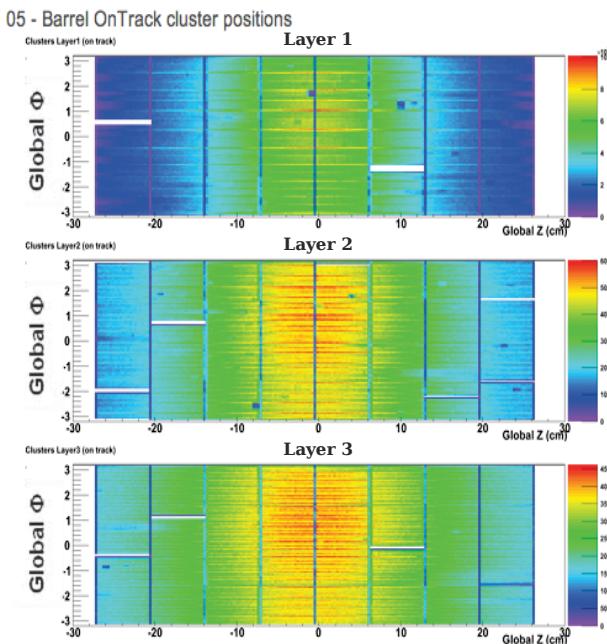
6

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Pixel operation in 2010



- 98.7% alive barrel modules.



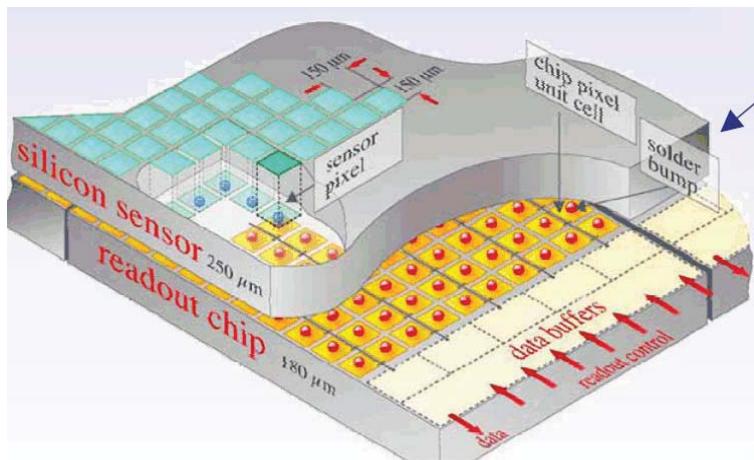
status Aug 2010

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7

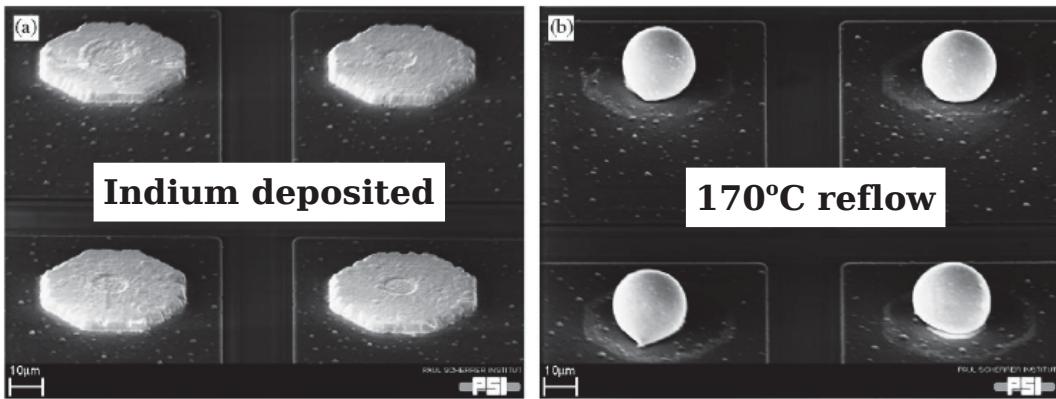
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Hybrid pixel detectors



**Silicon sensors with
100 × 150 μm^2 pixels,
bump bonded to
CMOS readout chips.**

**Requires special bump
bond technology.
Cost driver: 2c/bump.**



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8

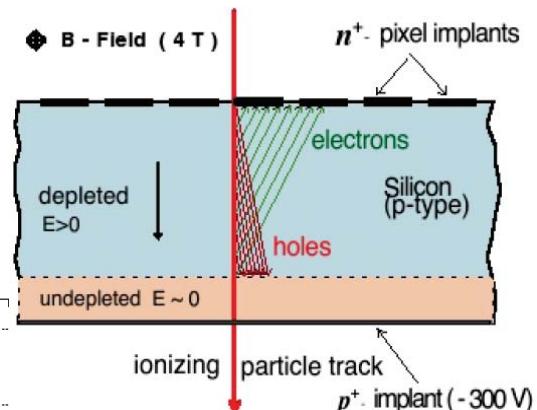
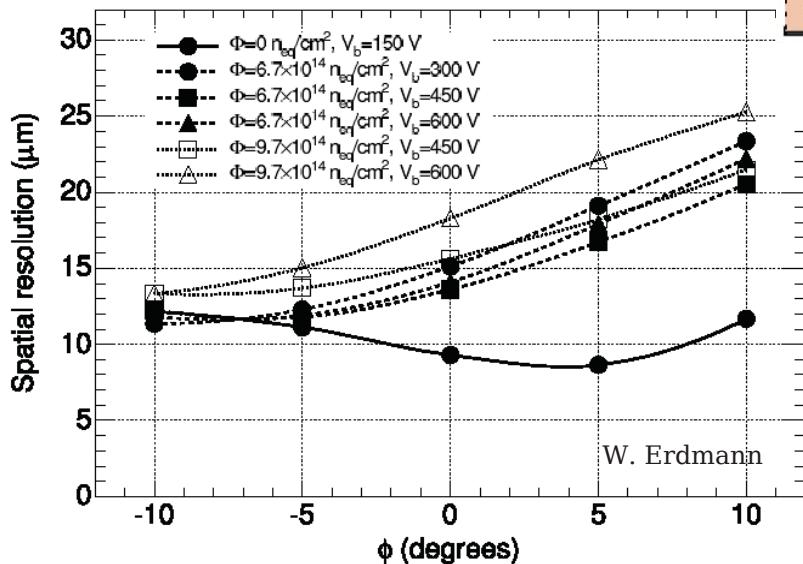
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CMS Pixel hit resolution

Drift in crossed E and B fields:

**Lorentz angle ($\tan \alpha_L = \mu B$) is
 $\sim 28^\circ$ for e in pure Si at 3.8 T.**

Leads to beneficial charge sharing.



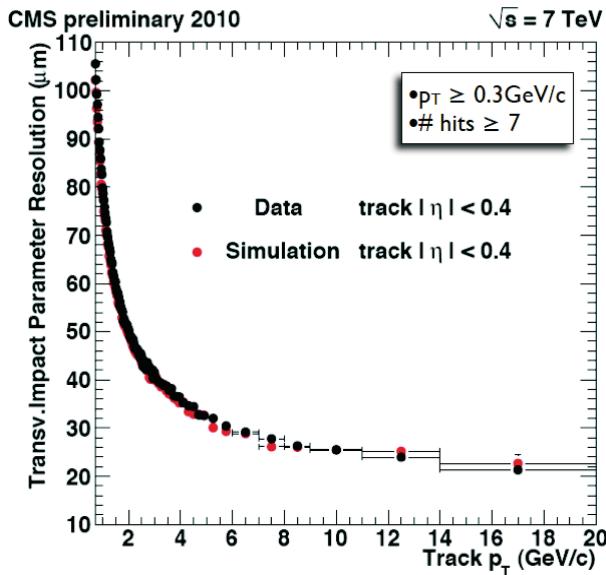
a hit resolution
of 12 μm has been
achieved in 2010
collision data.

D. Pitzl (DESY): CMS Pixel Upgrade

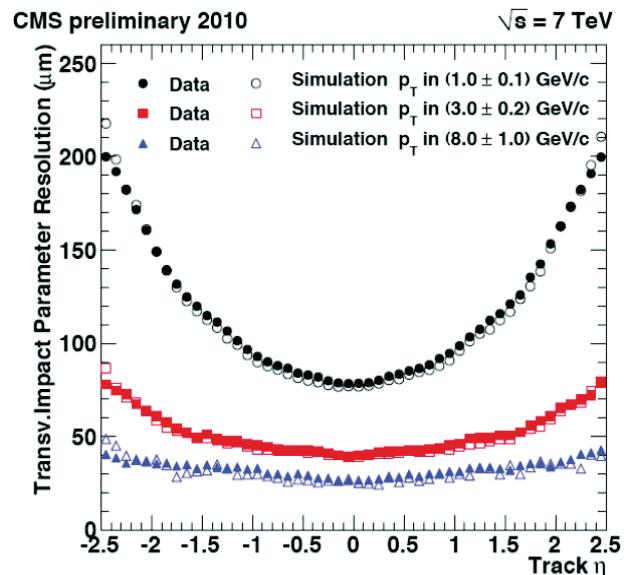
9

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CMS track impact parameter resolution

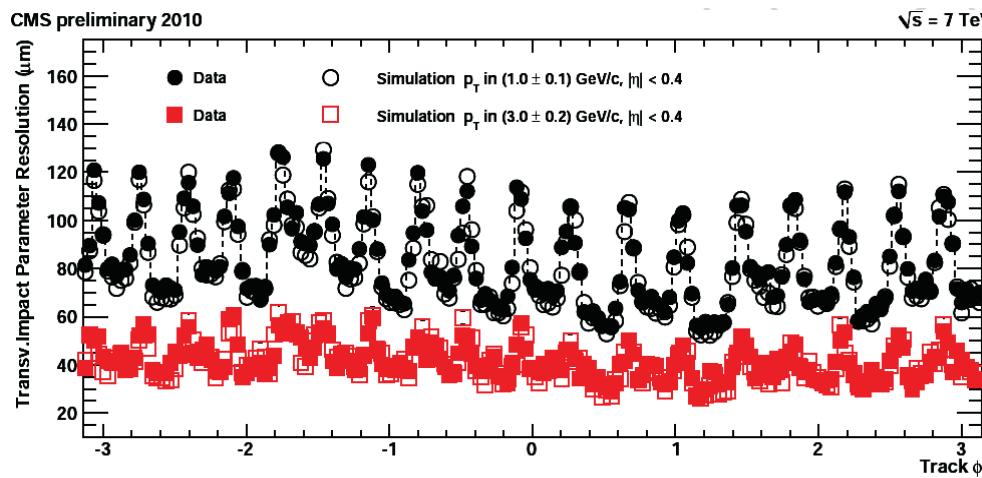


Reach 20 μm
at high momentum.
Ultimately expect 12 μm .



Limited by multiple
scattering at low momenta
and/or high rapidity.

CMS impact parameter resolution



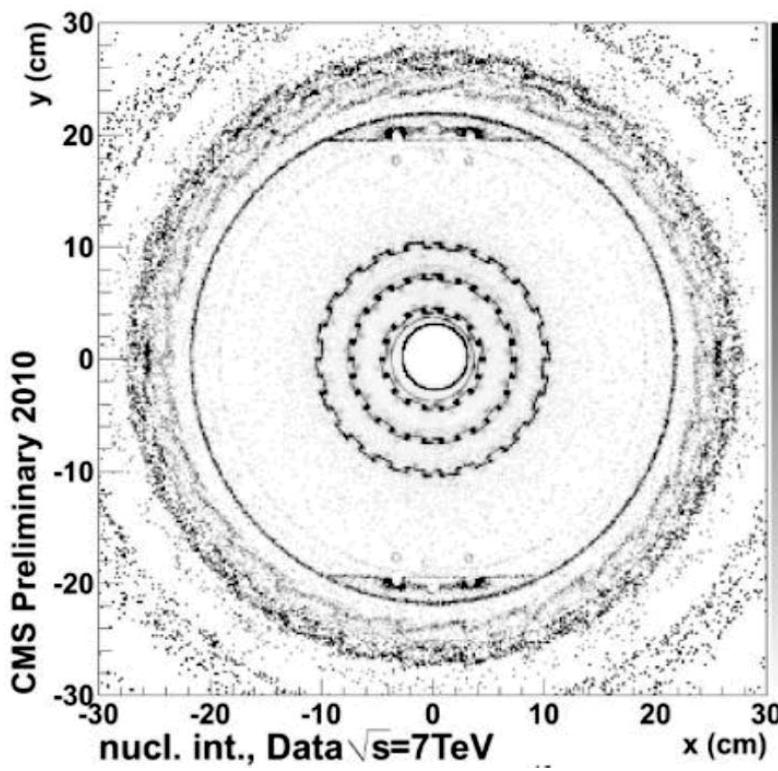
- 18-fold ϕ structure due to pixel cooling pipes visible at low p_T .
- Well described by the detector simulation.

D. Pitzl (DESY): CMS Pixel Upgrade

11

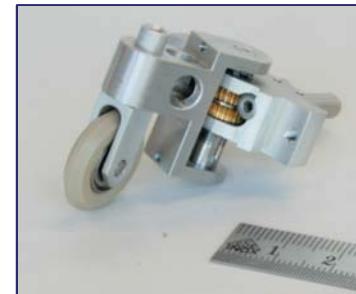
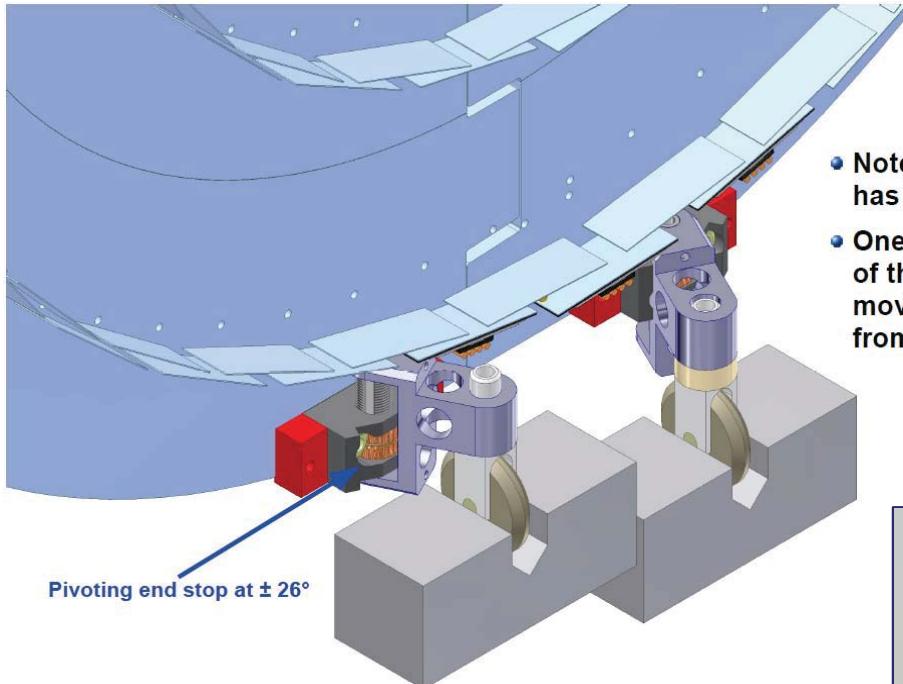
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Nuclear imaging



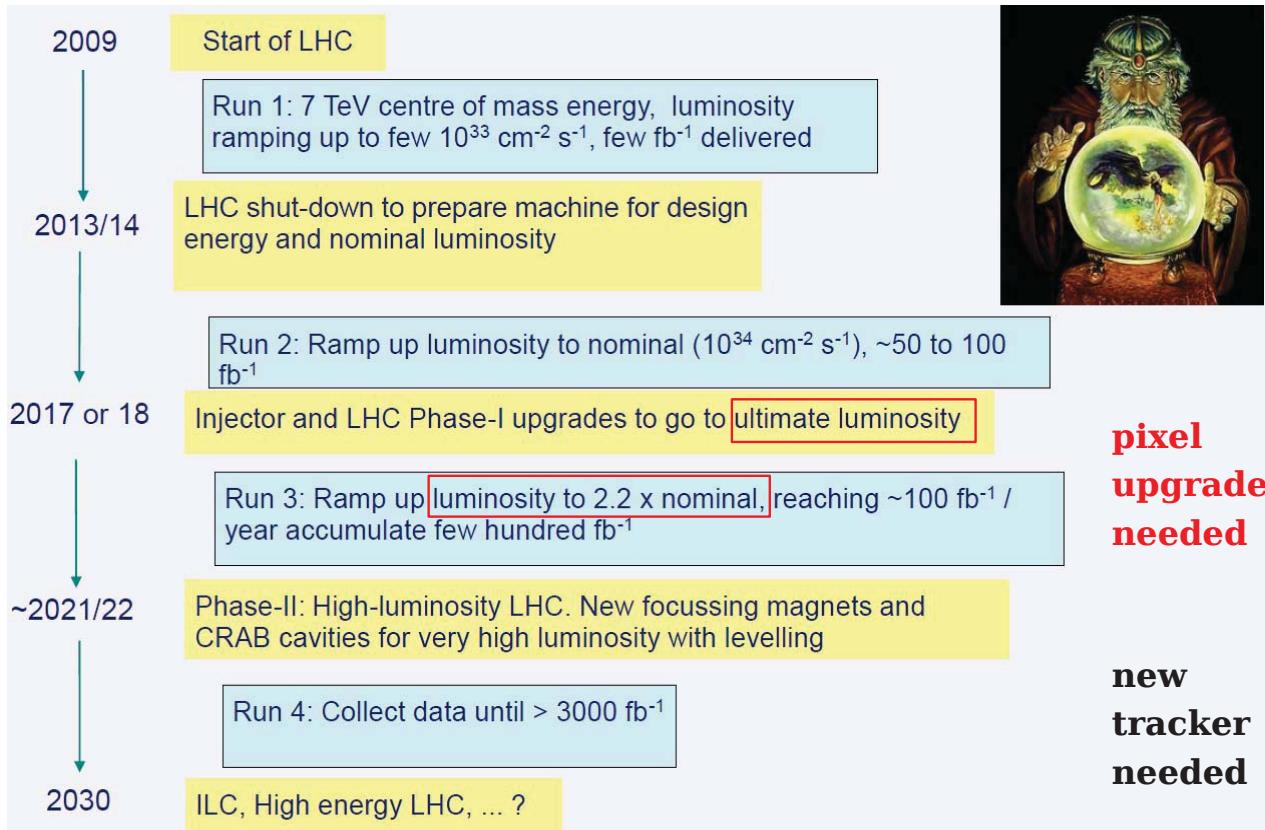
- Reconstructed nuclear interaction vertices.
 - ▶ Barrel pixel region.
- CMS tracker is shifted by ~ 3 mm relative to the machine beam pipe.
 - ▶ Upgrade: center pixel around pipe!
- Pixel modules, cooling pipes and support rails visible.
 - ▶ Upgrade: reduce the material budget!

CMS Barrel pixel adjustable wheels

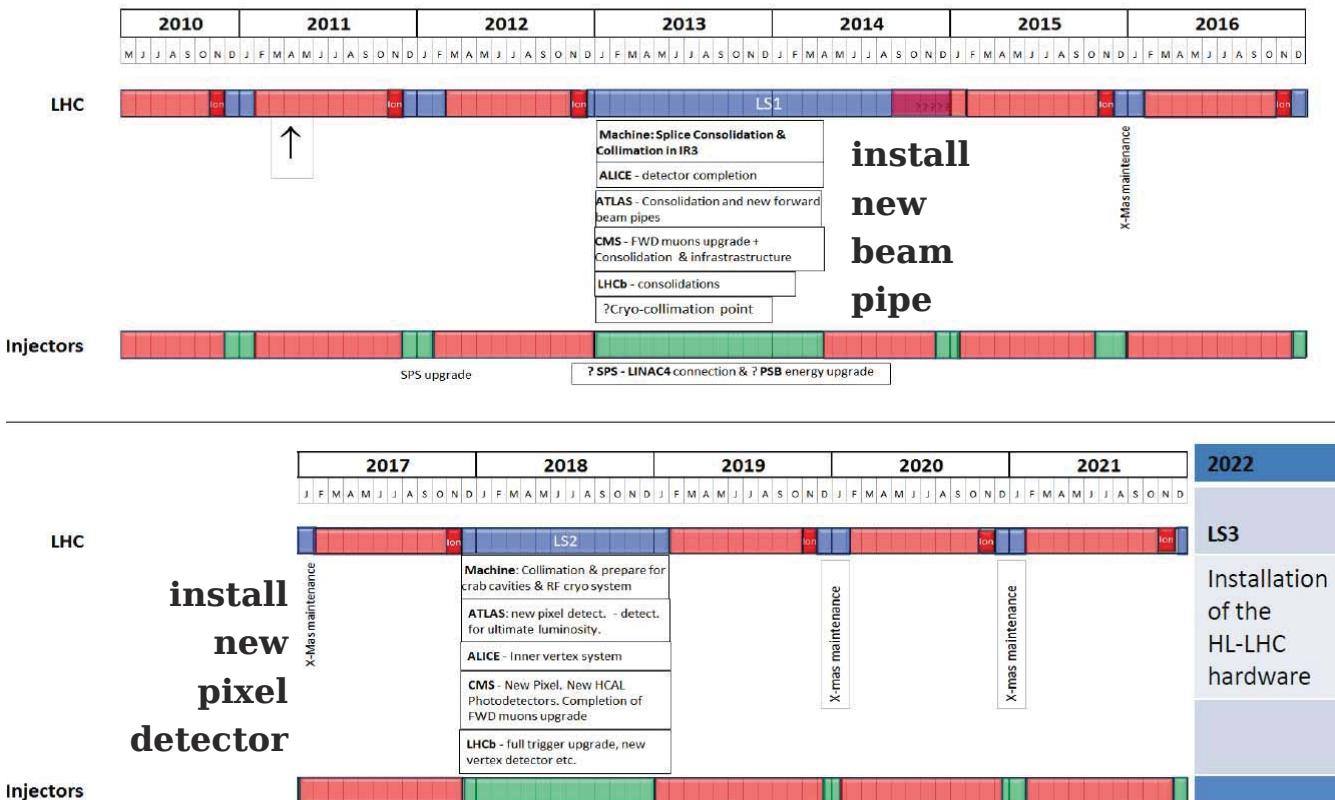


**Mechanical mock-up will be prepared.
Test installation procedure in early 2014.**

LHC plan (S. Bertolucci PLHC 2011)



LHC 10 year plan as of June 2011



D. Pitzl (DESY): CMS Pixel Upgrade

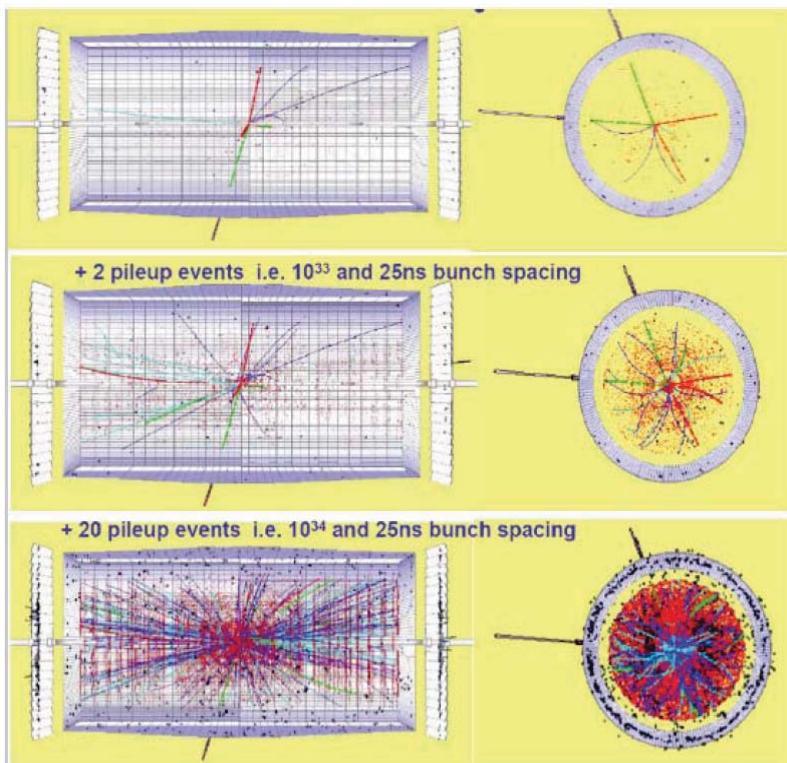
15

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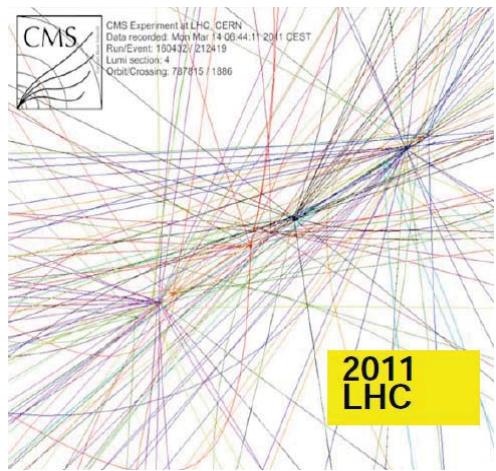
Event pile-up at high luminosity



Simulation



Data 2011:
7 pile-up events
at $2 \cdot 10^{33}$ and 50 ns
bunch spacing

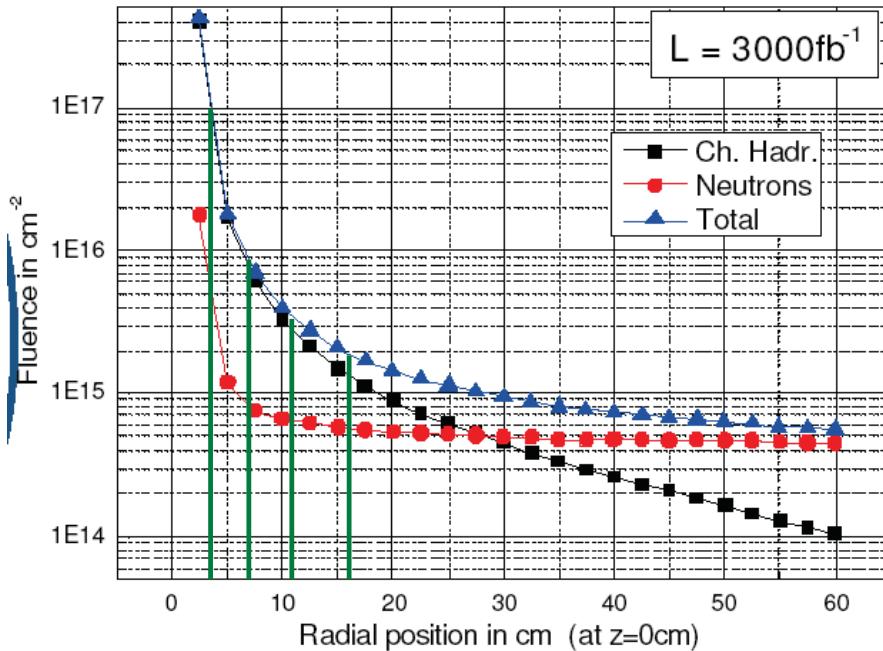


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16

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Particle fluence



- $3000 \text{ fb}^{-1} = 20 \text{ years.}$
- This decade: $300 \text{ fb}^{-1}.$
- Pixel region: dominated by pions.
- Layer at $R = 3 \text{ cm}:$
 - flux $500 \text{ MHz/cm}^2,$
 - may need replacement every year ($200 \text{ fb}^{-1}.$)

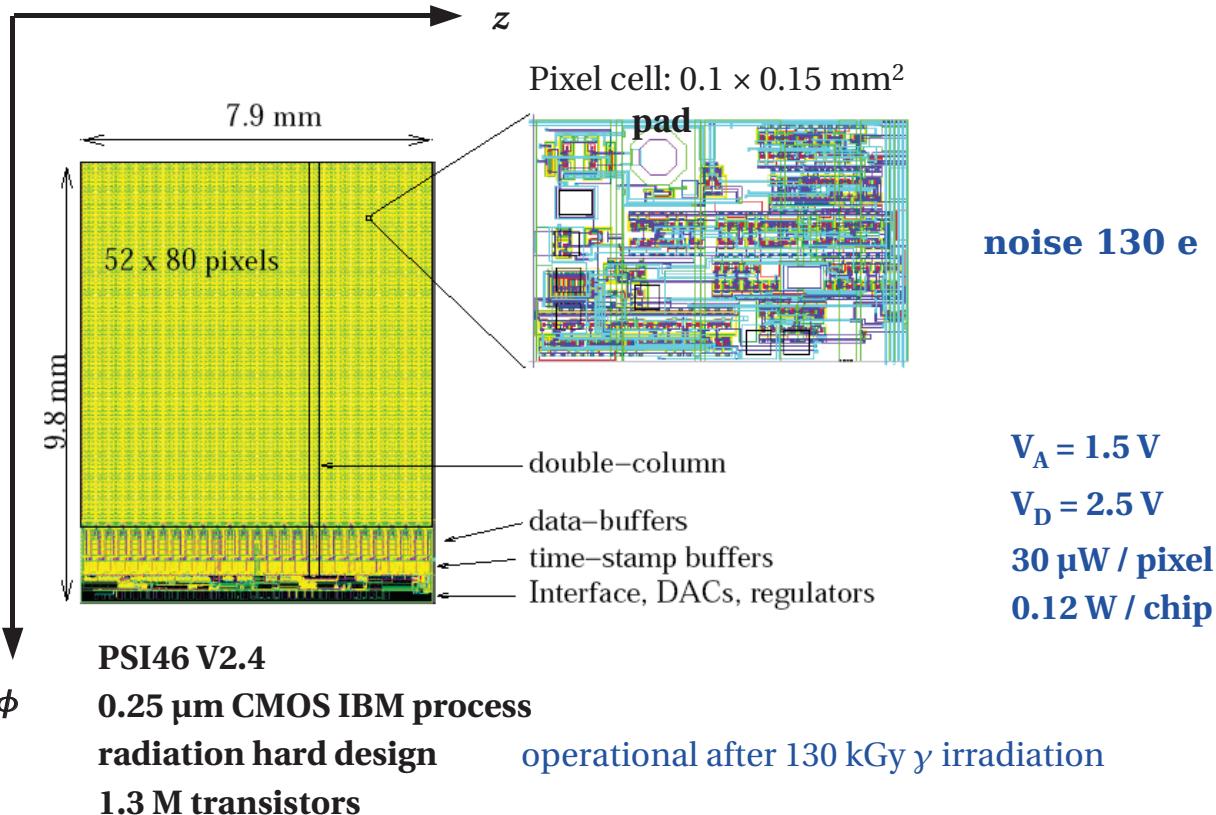
F. Hartmann, sensor testing, CMS Tracker Week Sep 2009
<http://indico.cern.ch/conferenceDisplay.py?confId=47301>

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17

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CMS Pixel Chip



Double column readout

Sources of inefficiency:
now → upgrade

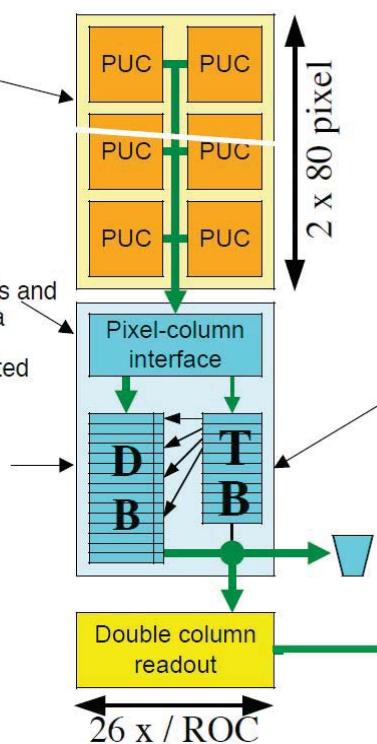
Pixel busy:
pixel insensitive until hit transferred to data buffer
(column drain mechanism)

2BC → 1BC

Double column busy:
Column drain finds hit pixels and transfers hits from pixel to data buffer. Maximum 3 pending column drains requests accepted

3 → 8 pending

Data Buffer full:
size: **80** (32)



Double column:

2×80 pixel, 0.024 cm^2

L1 trigger:

after 3.2 us (130 BC).

at $2 \cdot 10^{34}$, 25 ns, 29 mm:
0.2 tracks / DC / BC,
25 tracks in buffers.

Timestamp Buffer full:
size: **24** (12)

Readout and double column reset:
Wait for token, reset after r/o

40 MHz analog readout
→ **160 MHz digital**

Data loss mechanisms

Present PSI46 readout chip simulated at LHC design luminosity

Pythia physics generator + detector and chip simulation:

Pixel busy:

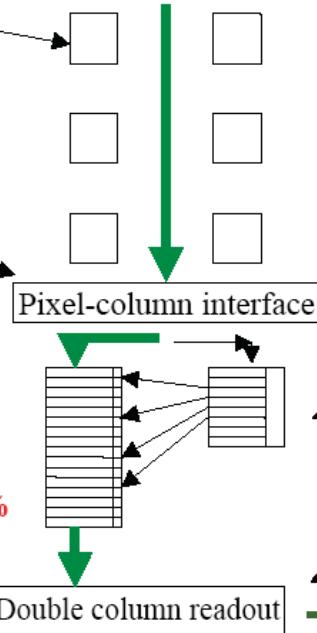
0.04% / 0.08% / 0.21%
pixel insensitive until hit transferred to data buffer
(column drain mechanism)

Double column busy:

0.004% / 0.02% / 0.25%
Column drain transfers hits from pixel to data buffer.
Maximum 3 pending column drains requests accepted

Data Buffer full:

0.07% / 0.08% / 0.17%



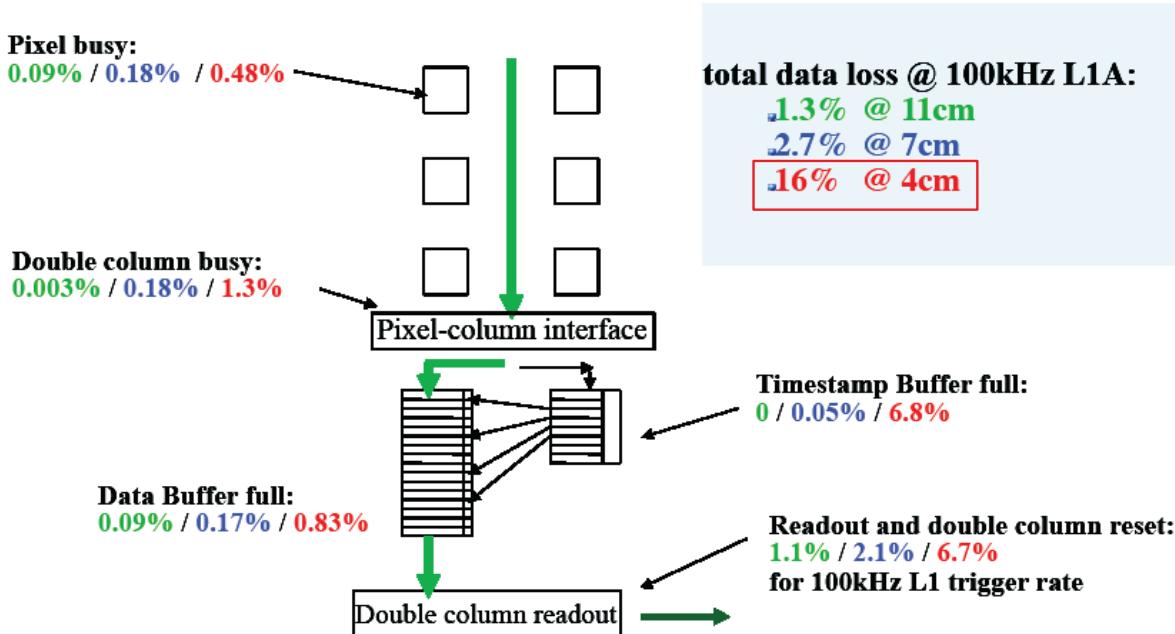
- **1xLHC: $10^{34} \text{ cm}^{-2} \text{s}^{-1}$**
- **11 cm / 7 cm / 4 cm layer**
- **total data loss @ 100kHz L1A:**
 - **0.8%**
 - **1.2%**
 - **3.8%**

Timestamp Buffer full:
0 / 0.001% / 0.17%

Readout and double column reset:
0.7% / 1% / 3.0%
for 100kHz L1 trigger rate

Data loss mechanisms

Present PSI46 readout chip simulated at **2 \times** LHC design luminosity

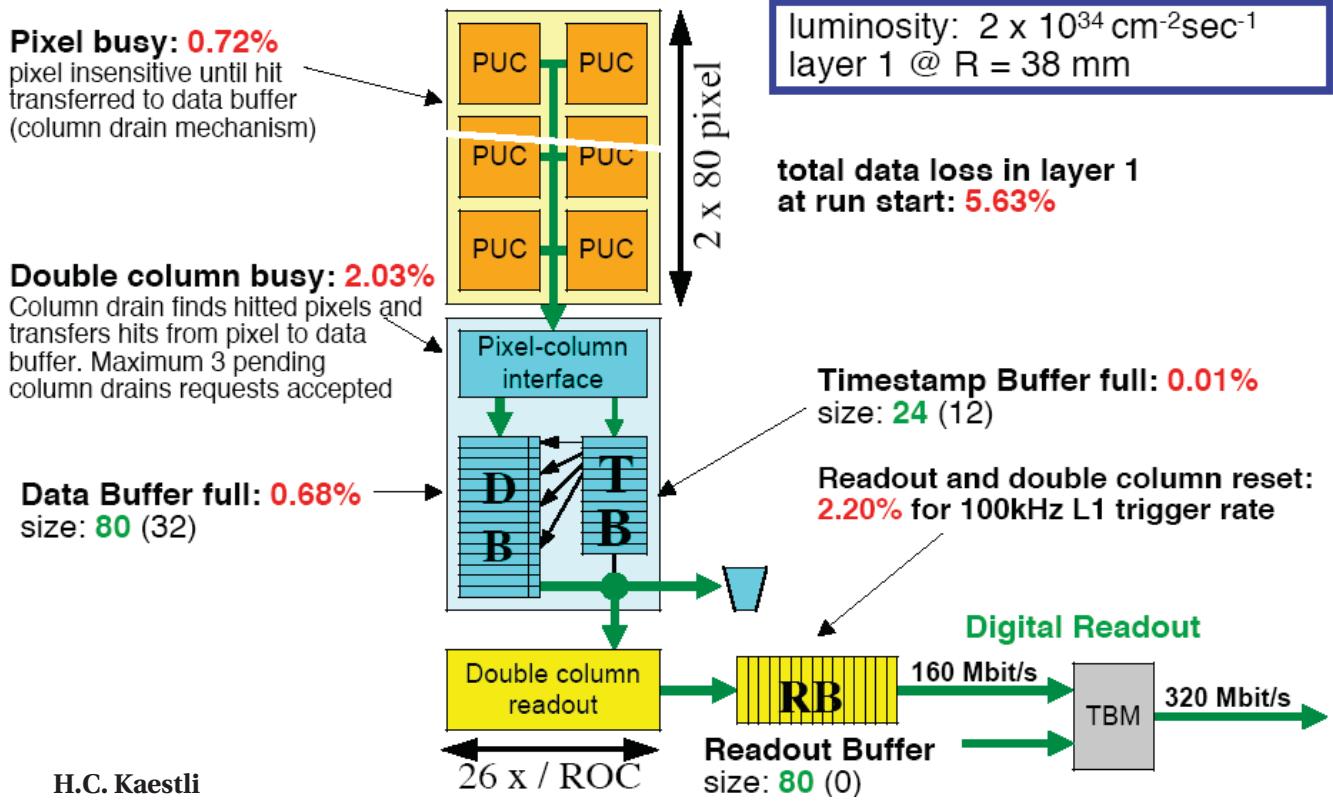


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21

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Data loss with extended buffering



H.C. Kaestli
Oct 2009

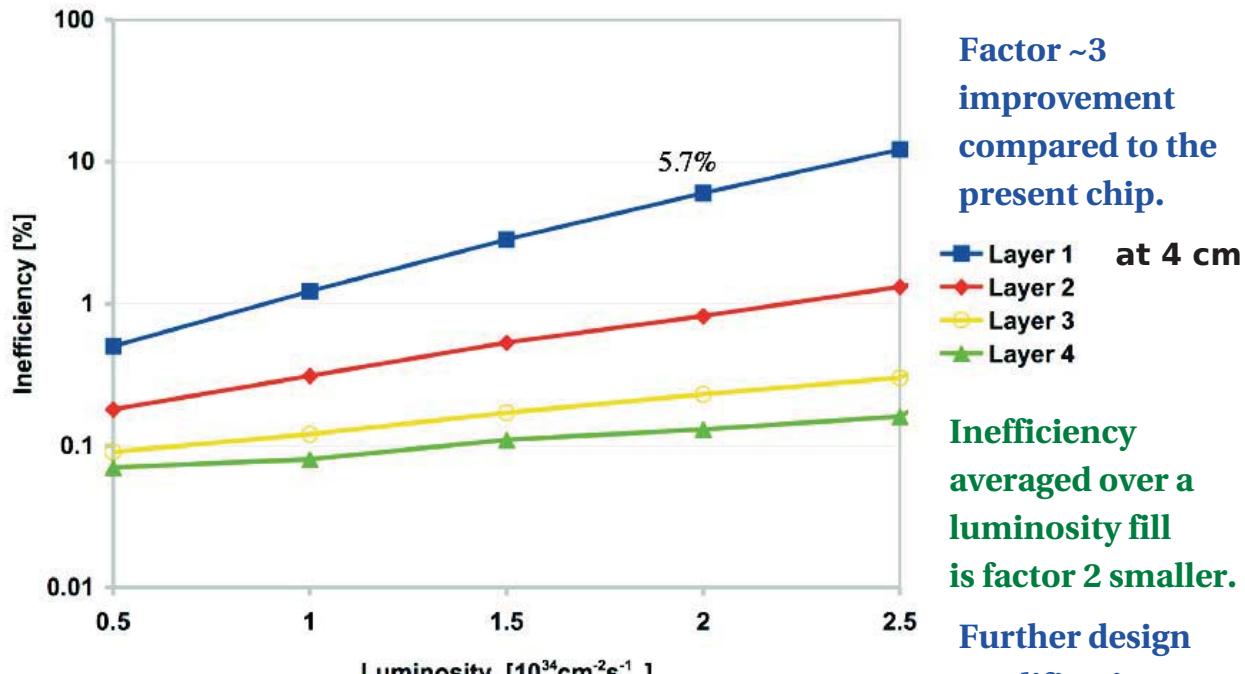
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22

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Data loss vs luminosity

Pixel readout chip simulation with increased buffering



H.C. Kaestli
Oct 2009

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23

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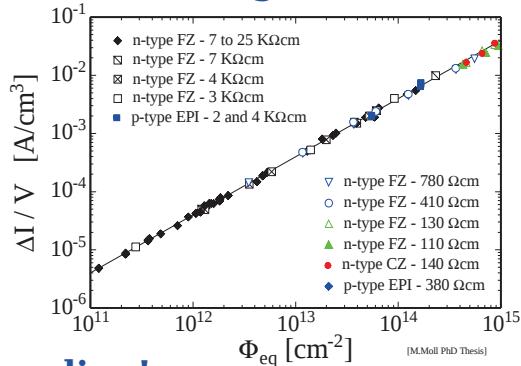
Inefficiency averaged over a luminosity fill is factor 2 smaller.
Further design modifications under study: aim for 2.5% at $2 \cdot 10^{34}$

Radiation damage in silicon

- Leakage current:
 - $I / V_{ol} = \alpha \Phi$ (fluence Φ [particles/cm²])
 - all silicon materials (FZ, Cz, epi) have the same damage α .
 - only cooling helps to reduce leakage current (factor 2 / 8°C).
- Space charge creation ('type inversion'):
 - leads to high depletion voltage at high fluence.
 - oxygenated silicon is better (DOFZ, mCz).
 - cooling reduces activation of defects.
- Charge trapping:
 - reduces charge collection efficiency
 - collecting electrons (n-in-p or n-in-n) is better than holes (p-in-n).
 - no 'defect engineering' method known to help.
 - Charge amplification at high bias, earlier in thin sensors or 3D.

Radiation damage effects in silicon

leakage current

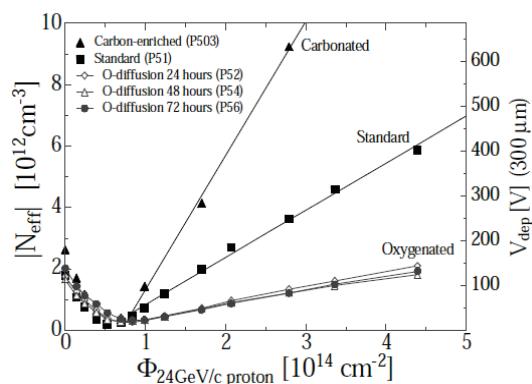


cooling!

factor 1/2

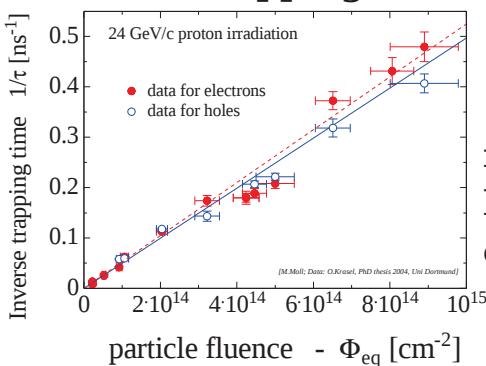
every -8°C

depletion voltage



oxygenated Si used!
Keep Si cool to avoid activation of defects.

trapping



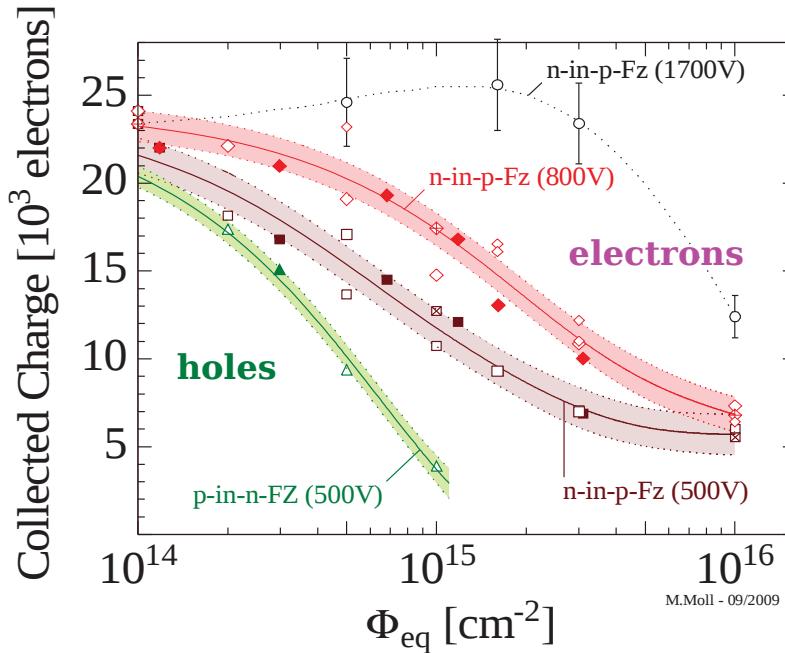
no known cure

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25

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Silicon charge collection vs fluence



FZ Silicon Strip Sensors

- n-in-p (FZ), 300μm, 500V, 23GeV p [1]
- n-in-p (FZ), 300μm, 500V, neutrons [1,2]
- n-in-p (FZ), 300μm, 500V, 26MeV p [1]
- n-in-p (FZ), 300μm, 800V, 23GeV p [1]
- n-in-p (FZ), 300μm, 800V, neutrons [1,2]
- n-in-p (FZ), 300μm, 800V, 26MeV p [1]
- n-in-p (FZ), 300μm, 1700V, neutrons [2]
- p-in-n (FZ), 300μm, 500V, 23GeV p [1]
- p-in-n (FZ), 300μm, 500V, neutrons [1]

References:

- [1] G.Casse, VERTEX 2008 (p/n-FZ, 300μm, -30°C, 25ns)
- [2] I.Mandic et al., NIMA 603 (2009) 263 (p-FZ, 300μm, -20°C to -40°C, 25ns)

Detectors made from oxygenated Si and collecting electrons should operate up to a few $10^{15} n_{eq}/cm^2$ with tolerable efficiency and resolution degradation: that's several $100 fb^{-1}$ at $R = 3$ cm.

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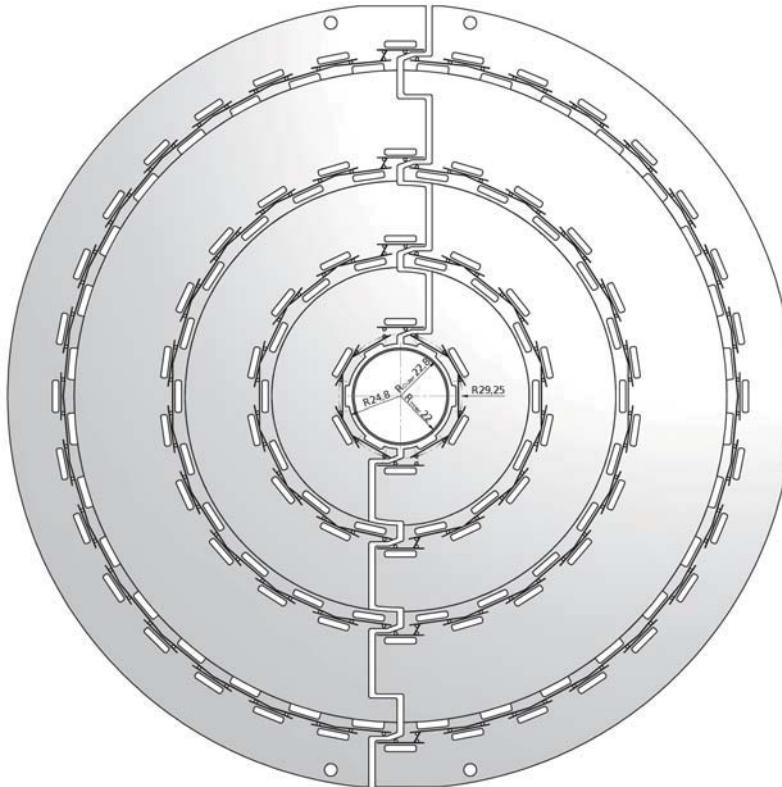
26

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Further upgrade considerations

- Smaller beam pipe for improved impact parameter resolution:
 - B-tagging
- 4th layer for better track seeding efficiency and improved stand-alone tracking:
 - High Level Trigger
- Less material (mechanics, chips, cooling, cables):
 - less multiple scattering, photon conversions, nuclear interactions

CMS pixel upgrade: 4 layers



2 identical half-shells.
1184 modules (79M pixels)
(1.6 × present barrel)

R₁ = 29 mm, 96 modules

CH

(reduce beam pipe diameter
from 59 to 45 mm)

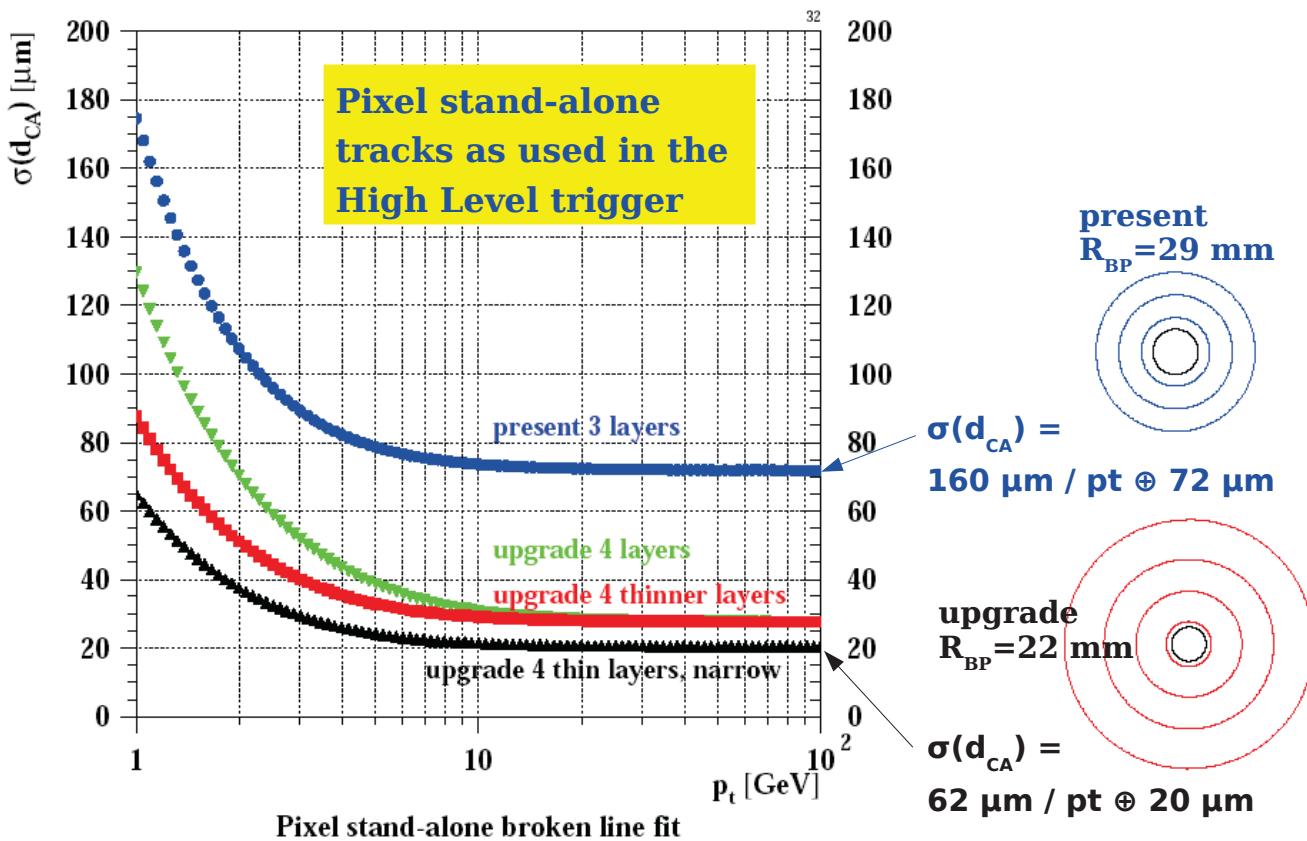
R₂ = 68 mm, 224 modules

CH

R₃ = 109 mm, 352 modules
Italy, CERN

R₄ = 160 mm, 512 modules
Germany

Pixel track impact parameter resolution



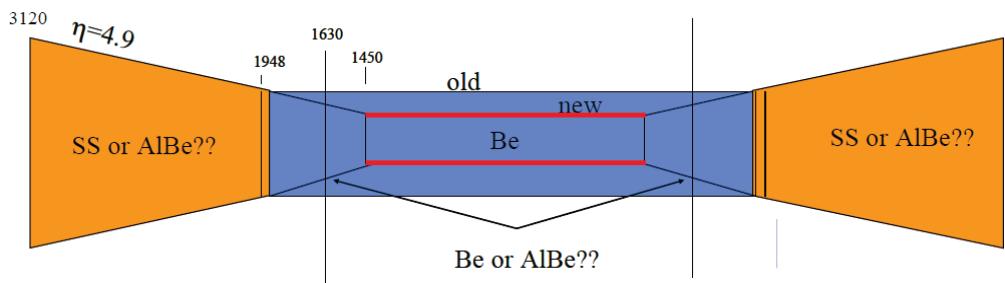
D. Pitzl (DESY): CMS Pixel Upgrade

29

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29

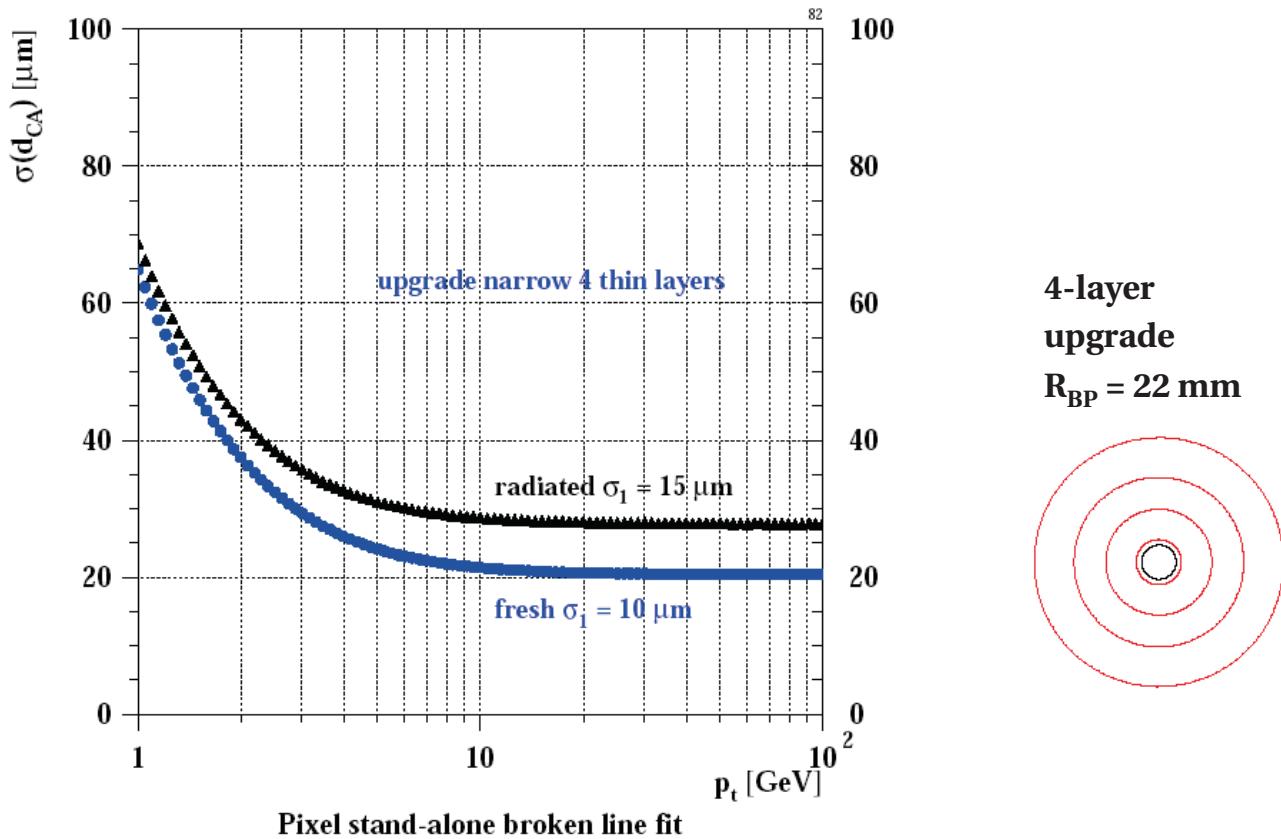
CMS new central beam pipe



**new central beam pipe with
43.6 mm inner diameter
(present: 58 mm)
accepted by LHC machine.
Order will be placed soon.
Aim to install Jan 2014.**

Austin Ball
June 2011

Radiation damage



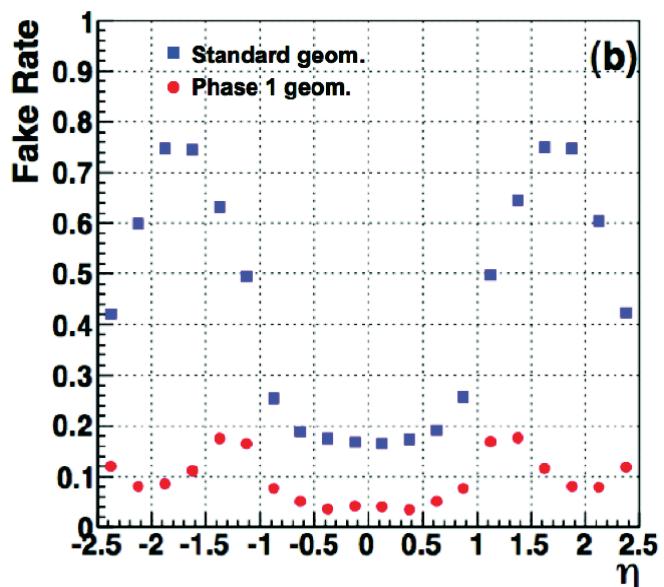
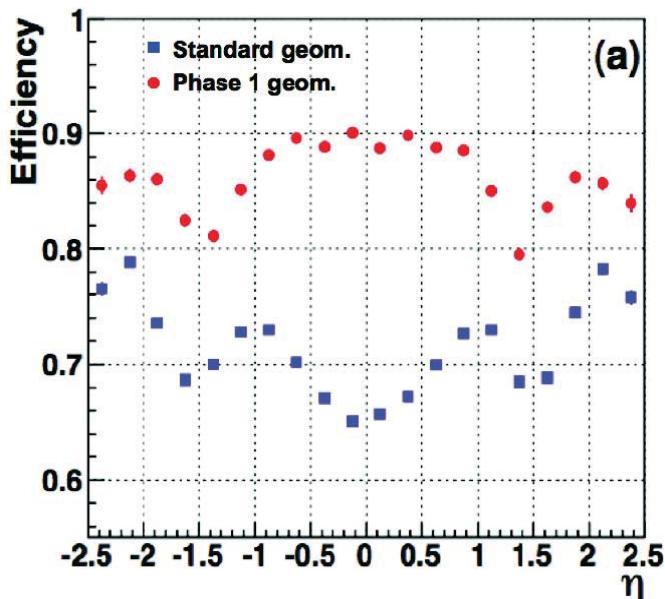
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31

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Tracking performance with pile-up 50

- t-tbar simulation with pile-up of 50 minimum bias events ($2 \cdot 10^{34}$ with 25 ns spacing).
- Pixel-based track seeding.



- 4-layer upgrade improves seeding efficiency. z-gaps remain

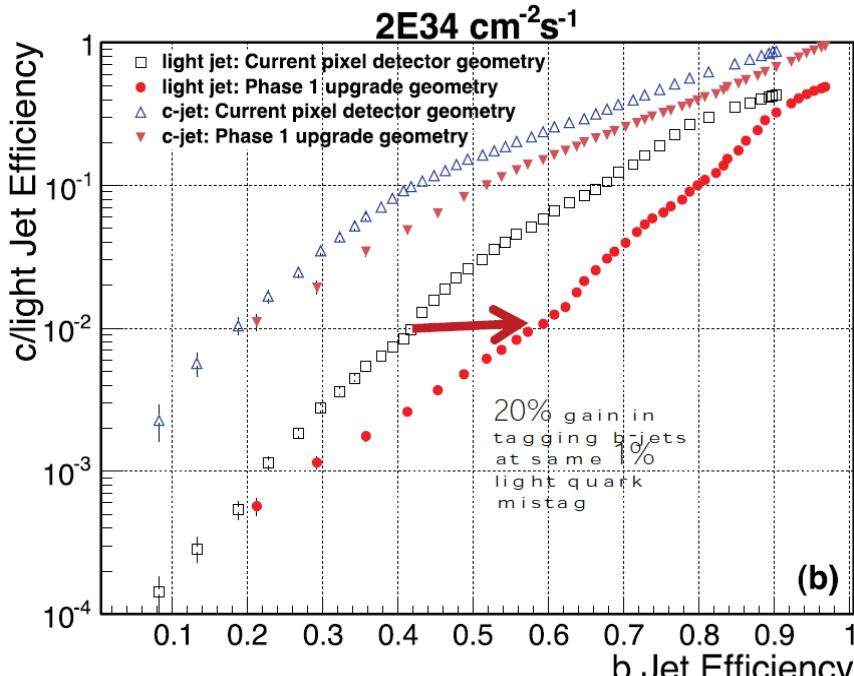
- 4-layer upgrade reduces fake rate.

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32

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b-tagging performance with pile-up 50



- Detailed simulation of the physics performance on going:
 - ▶ at high level trigger,
 - ▶ at full analysis level.
- 4-layer upgrade is needed to maintain present performance at high luminosity
 - ▶ Expect improved pixel b-tagging in the HLT.

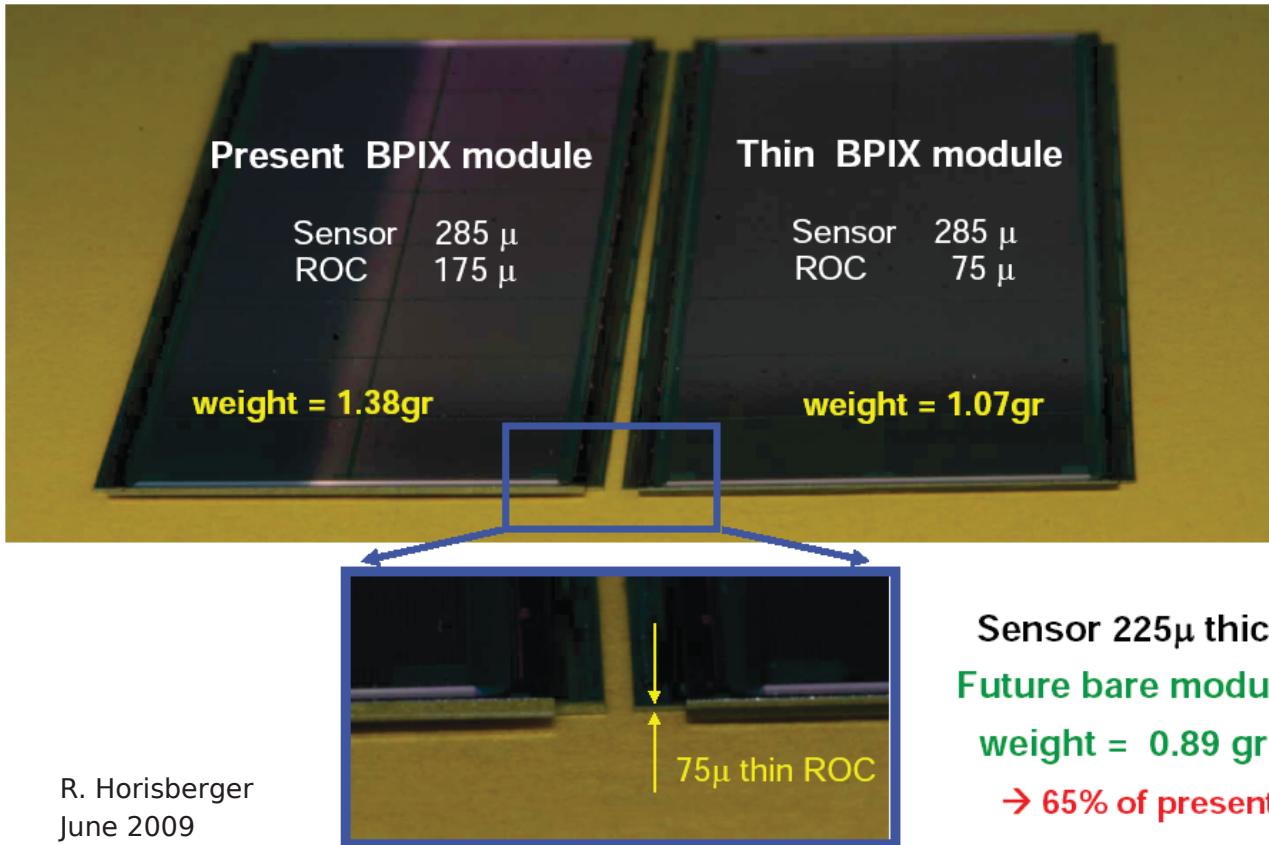
Pixel upgrade motivations

- Prepare for 2× higher luminosity than design: $2 \cdot 10^{34}/\text{cm}^2/\text{s}$:
 - ▶ maintain pixel efficiency
- Less material (mechanics, chips, cooling, cables):
 - ▶ less multiple scattering, photon conversions, nuclear interactions
- 4th layer for better track seeding efficiency and improved stand-alone tracking:
 - ▶ High Level Trigger
- Smaller beam pipe for improved impact parameter resolution:
 - ▶ B-tagging
- Add redundancy in the tracking system:
 - ▶ independent of the luminosity evolution

Pixel upgrade implications

- Prepare for $2\times$ higher luminosity than design: $2 \cdot 10^{34}/\text{cm}^2/\text{s}$:
 - Requires a new readout chip with more buffering.
- Less material:
 - Low mass supports, CO_2 cooling, optical converters outside the tracking volume.
- 4th layer for better track seeding efficiency and improved stand-alone tracking:
 - Digital readout and DC-DC power converters (have to use the same outer power cables and optical fibers)
- Smaller beam pipe for improved impact parameter resolution:
 - Accepted by LHC machine group.
- Add redundancy in the tracking system:
 - Be ready early, almost independent of the luminosity evolution.

CMS pixel upgrade



Upgrade carbon fiber frame



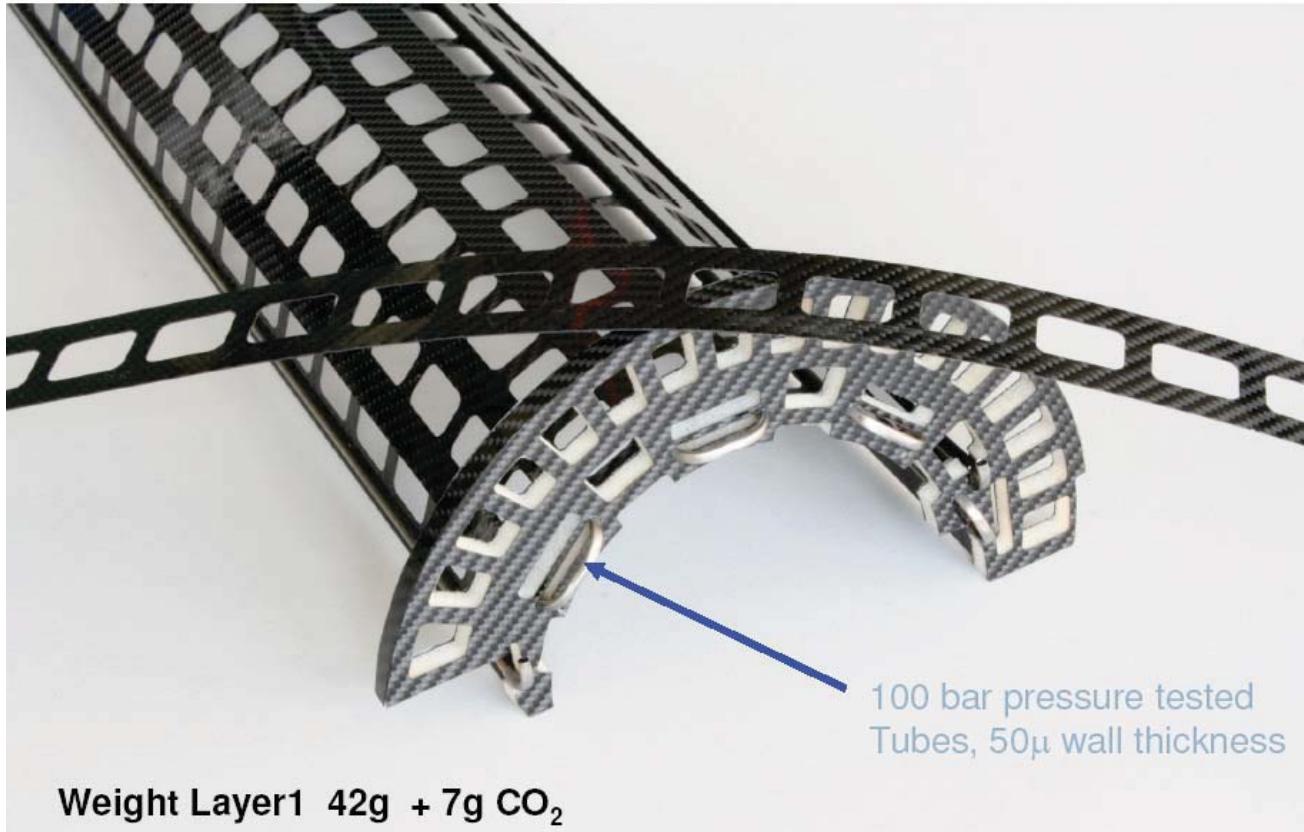
**Ultra-light weight carbon fibre frame and
airex end flange with pipes for CO₂ cooling.**

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37

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CMS pixel upgrade

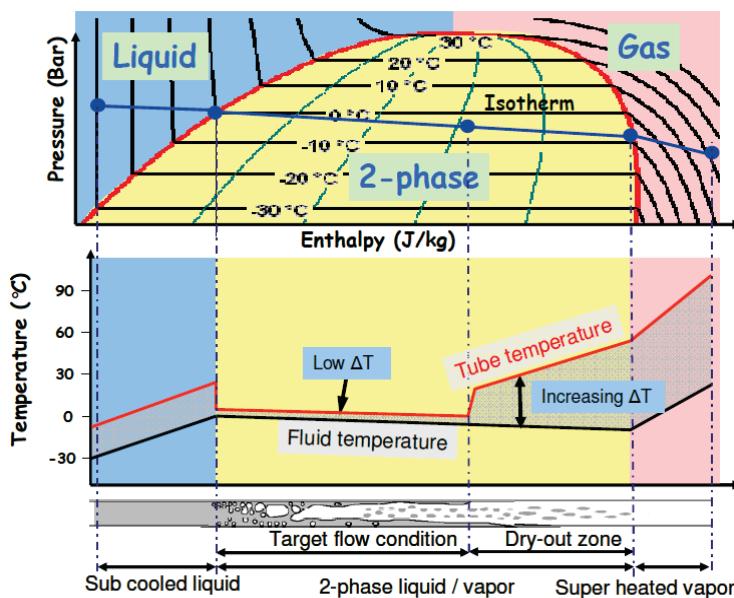


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38

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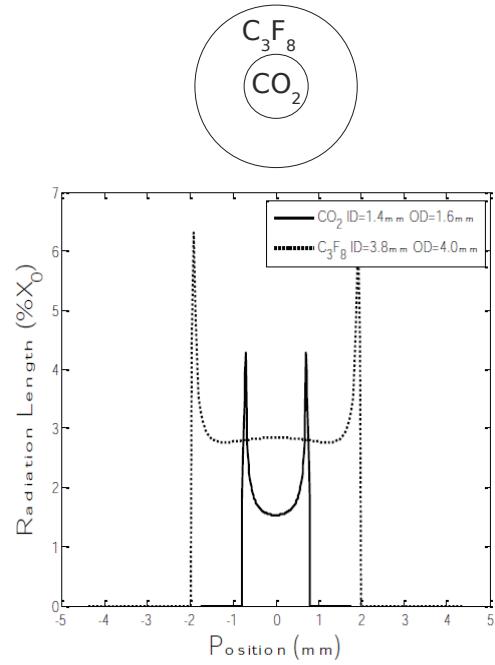
Upgrade: CO₂ cooling



- 2-phase CO₂ cooling: large latent heat
- operating at -35°C, good viscosity
- reduces Si leakage current
- reduces defect activation in Si

D. Pitzl (DESY): CMS Pixel Upgrade

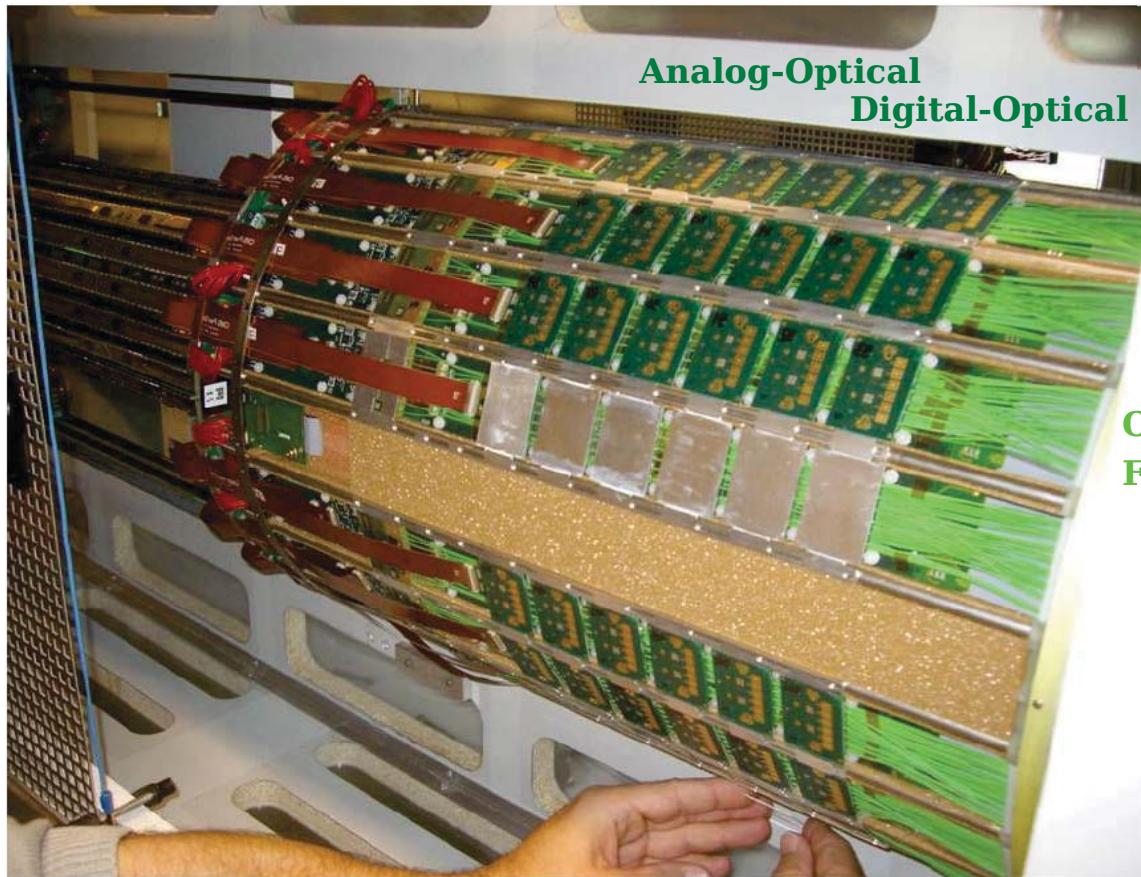
39



- Thin tubes, 50 bar
- material reduction

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Barrel Pixel services

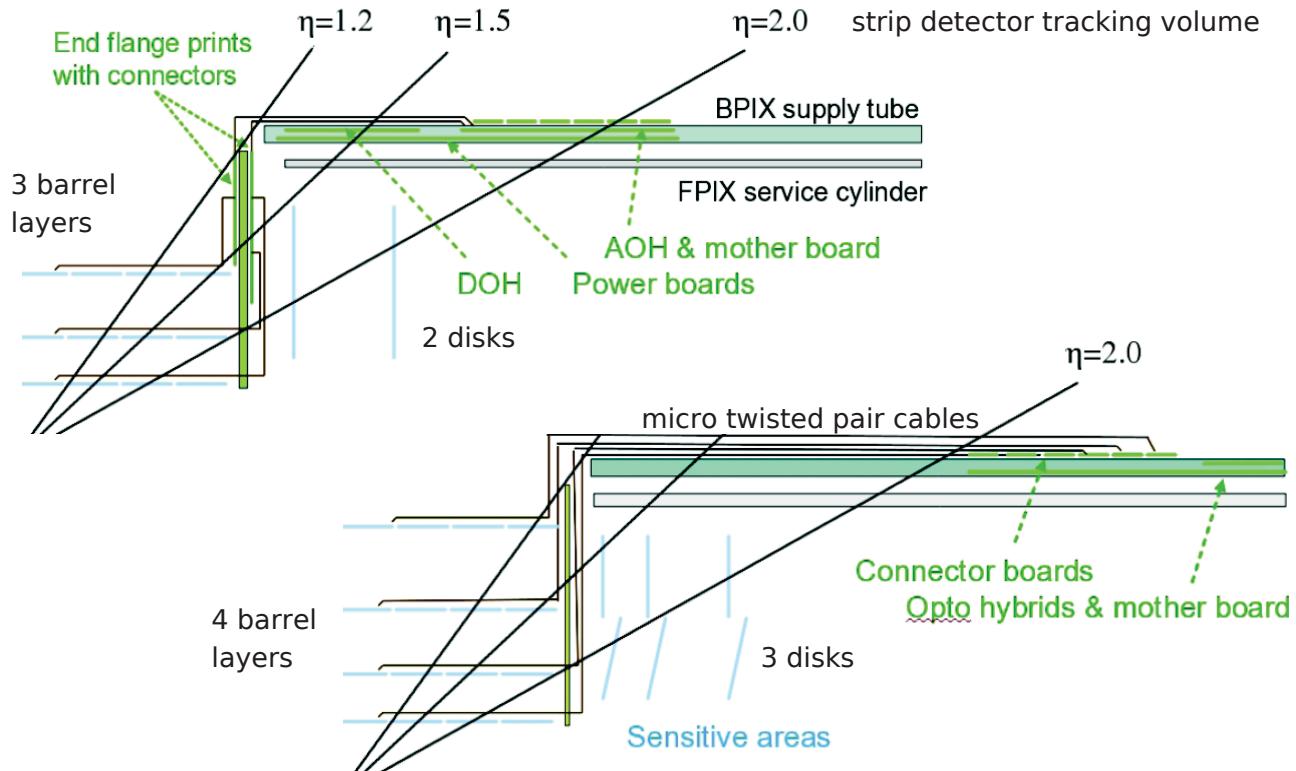


D. Pitzl (DESY): CMS Pixel Upgrade

40

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Moving readout material out of the tracking region

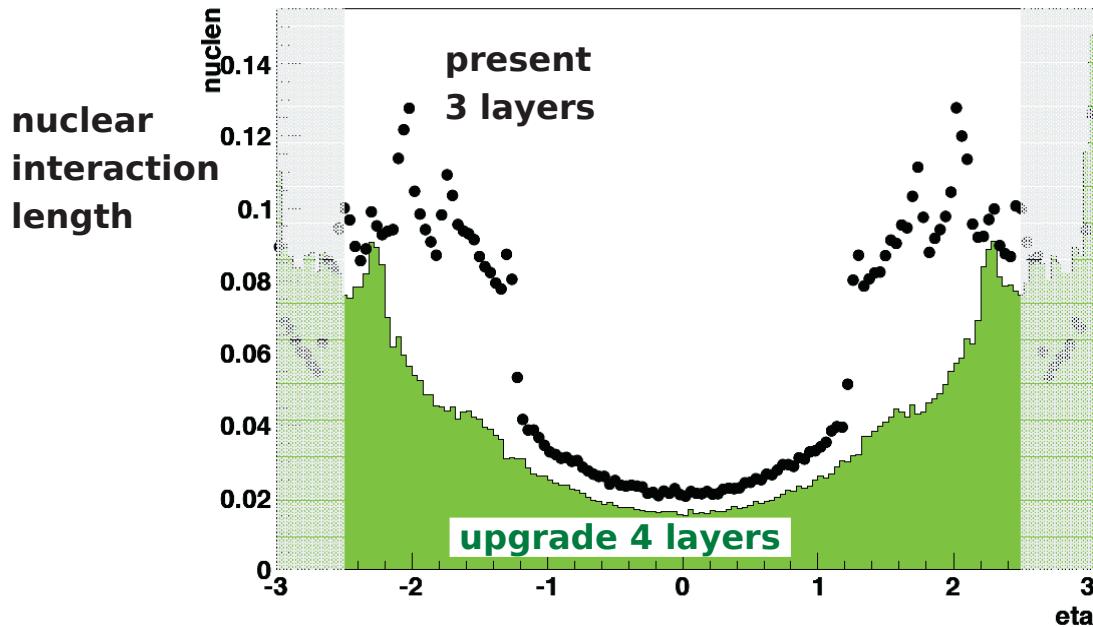


D. Pitzl (DESY): CMS Pixel Upgrade

41

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Barrel pixel material budget



Up to 12% of all hadrons are lost due to nuclear interactions in the present pixel barrel.

Upgrade will give up to factor 2 reduction.

Services



- DC-DC converter developed in Aachen:
 - air-core coil, 10V → 3.3 V, 3 A, $\eta=75\%$
 - radiation resistant AMIS 2 chip (CERN), switching at 1.2 MHz,
 - optimized design for low noise.

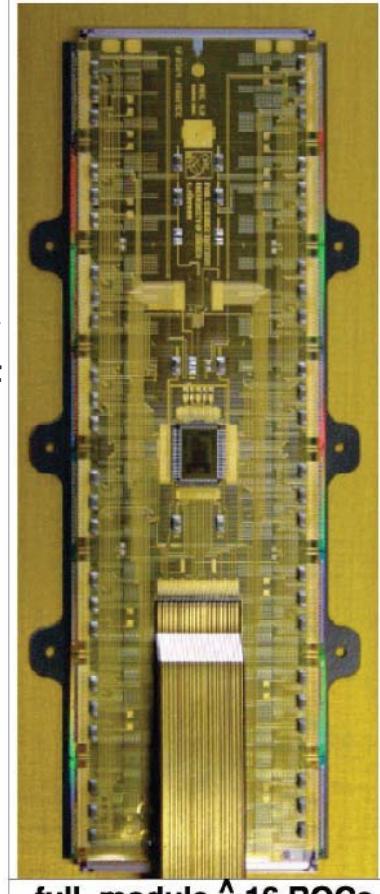
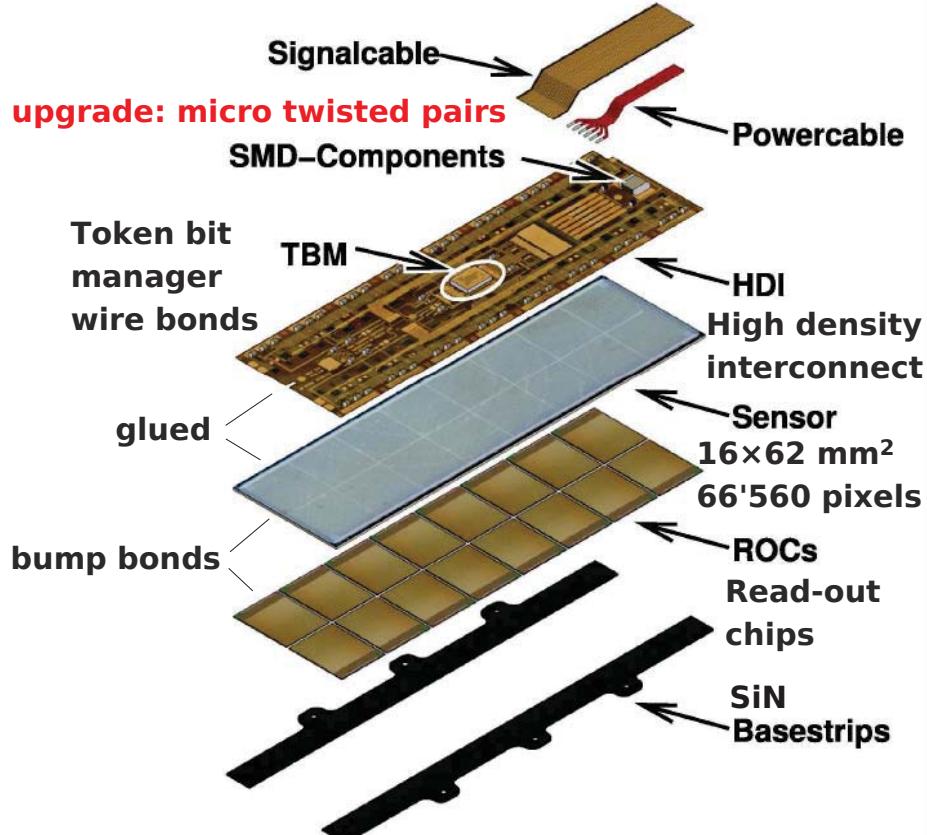
- CMS tracker cable channels are full:
 - have to use the existing services.
- Optical fibers:
 - go from 40 MHz analog to 320 MHz digital readout.
- Power:
 - Use DC-DC converters at the detector.
- Sensor bias:
 - 600 V → 1000 V.
- CO₂ cooling:
 - pipe-in-pipe for 100 bar.

D. Pitzl (DESY): CMS Pixel Upgrade

43

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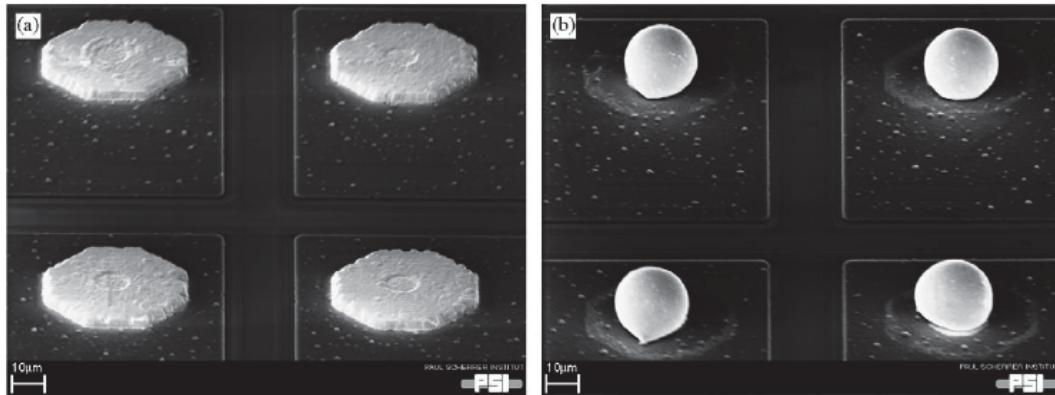
CMS barrel pixel module



D. Pitzl (DESY): Cl

full-module ≈ 16 ROCs

Bump bonding at PSI



**Indium pads deposited
on the Si sensor.**

**After re-flow at 150°C in
 N_2 and CH_2O_2 atmosphere.
15 μm diameter.**

**Involves many steps:
sputtering,
photo lithography,
etching...**

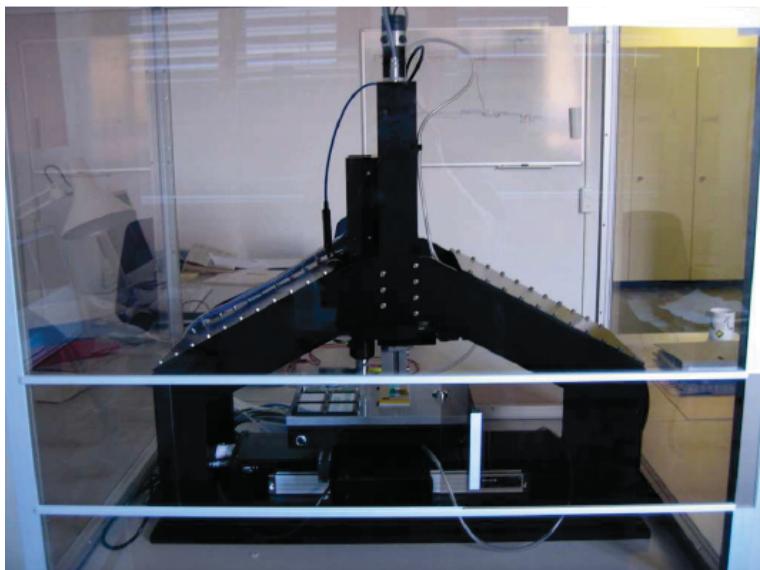
Ch. Broennimann et al.: Development
of an Indium bump bond process for
silicon pixel detectors at PSI
NIM A565(2006)303-8

D. Pitzl (DESY): CMS Pixel Upgrade

45

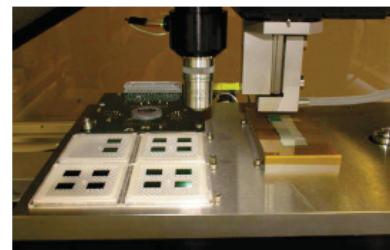
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Flip chip assembly at PSI

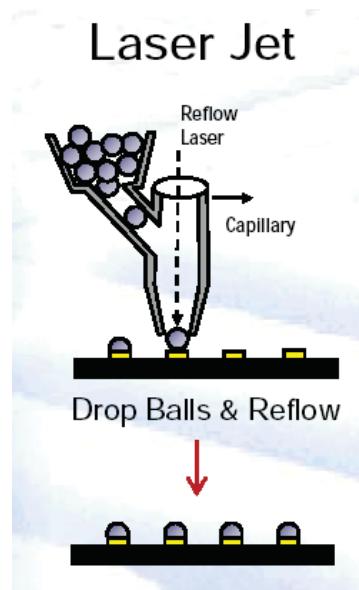
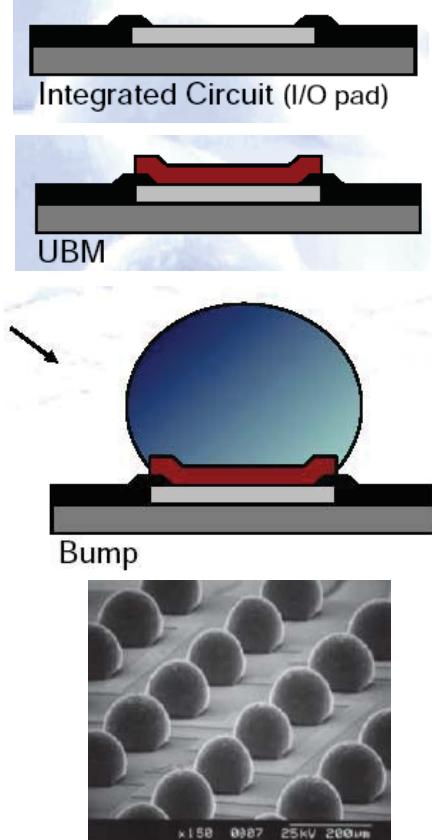


Precision x-y-z stage
Computer controlled
Commercially available.

- ▶ Precision: $1 \div 2 \mu m$
- ▶ Production rate:
 - ▶ 6 modules / day + tests
 - ▶ automated: 1 hr/module
- ▶ Bare module test:
 - ▶ IV-curve
 - ▶ ROC functionality
 - ▶ bump yield
 - ▶ rework: 80% success



Alternative



http://www.pactech.de/index.php?option=com_content&view=article&id=154&Itemid=21 68

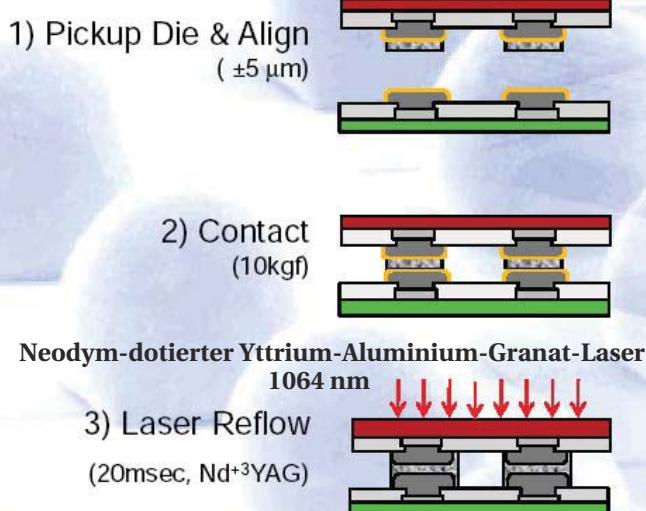
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47

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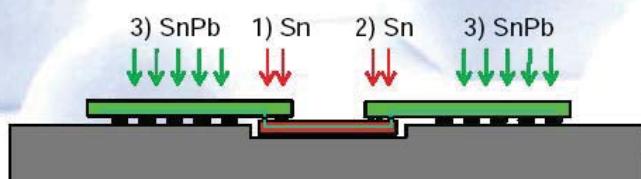
- Start with high-precision balls.
- Drop through capillary towards pad.
- Melt by laser pulse during fall.
- Solidify on pad.
- Step-motor controlled.
- 5 ball / second.
- 40 μm balls at 80 μm pitch possible now.
- 30 μm balls under development.

Laser reflow bonding

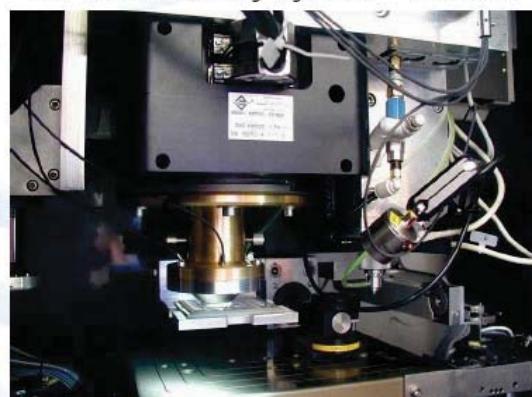


Neodym-dotierter Yttrium-Aluminium-Granat-Laser
1064 nm

Laser based assembly allows localized heating:



LaPlace Assembly System™ PacTech



Placement accuracy: +/- 15um: ~3000 - 5000 UPH
Placement accuracy: +/- 10um: ~2000 UPH
Placement accuracy: +/- 5um: ~1000 UPH
Placement accuracy: +/- 2.5um: ~500 UPH

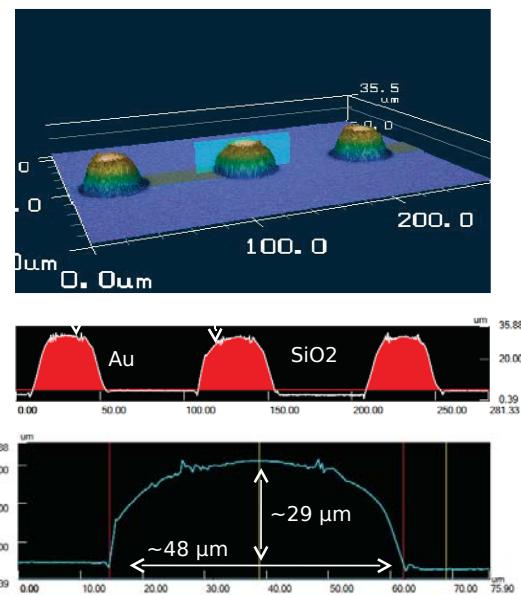
units
per
hour

- Selective to individual die
- Energy localized to bumped areas
- Ability to differentiate between solder alloys
- Low stress
- Minimizes IMC (time/temp)

PacTech test structures

Pac 2.7 Wafer from Pac Tech GmbH

- Two 200-mm Wafers with 275 Chips each
- 5-µm electroless Ni/Au UBM on both
- 40-µm SAC305 Solder Jetting with SB2 on one
- Wafer Sawing & Chip Singulation



Available since Dec 2010.
Used with 4 machines/vendors.

Karsten Hansen, DESY FEC

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49

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Pac Tech: SB2 Jet



Solder Ball Placer:

pre-formed balls are placed sequentially at 6-7 Hz
fused by laser heating
30 µm balls being certified, 40 µm ordered for test.

SET: FC 150 Flip-chip bonder



Industry standard, expensive, slow.
For placing and re-flow heating. Used at IZM.

SET: Kadett K1



Unitemp: RS-350-110



PSI design: cheapest, slow.
no > 50 mm heating chuck available.
Tacking Tests completed on small samples:
> 0.6 g/ball @ 155°C for chip & substrate.
Re-flow tests completed: OK.

Pac Tech: Laplace



RFA 300M



Novel Industry Standard: medium price
laser-assisted, fast.

Tacking Tests completed:
low force with chip at 195°C for 1s.
Reflow Tests completed: OK.

Novel FC 150 competitor: medium price.
Placing and re-flow heating, low-force, fast.

Tacking / re-flow tests under way.

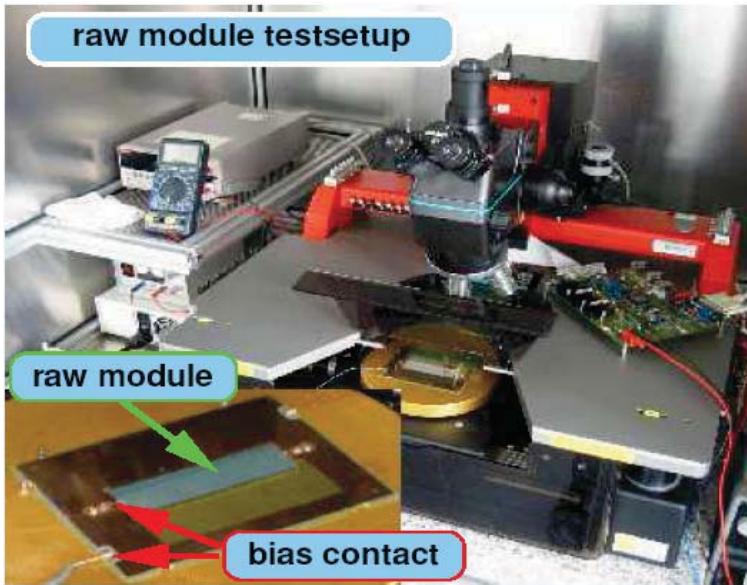
Finetech: FINEPLACER femto



Karsten Hansen, DESY FEC DESY Technisches Seminar, Zeuthen 22.11.2011

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Bare module test at PSI



Semi-automatic probe station at PSI:
load manually,
step and measure automatically.

- Test bare module after flip-chip bump bonding:
- Sensor I-V curve.
- Test 16 readout chips.
- Determine bump yield.
- Rework bad modules:
 - replace individual chips.

Probe station at DESY FEC

Süss Microtech PA 300 Probe Station

auctioned
from
Qimonda
in Dec 2009



Probe-Card Holder



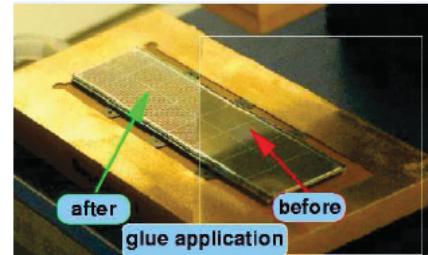
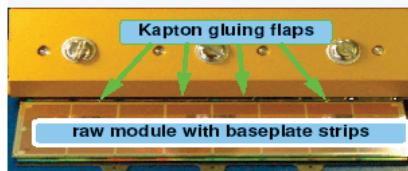
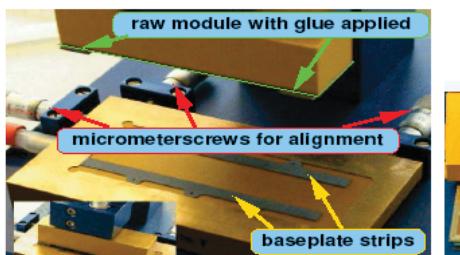
will order 42 needle probe card for testing ROCs after bump bonding.

up to 300 mm wafers
Semi-Automatic
Shielded
Thermo chuck -40 .. +125°C

Barrel pixel module assembly line at PSI



- ▶ Production rate:
 - ▶ 4 full + 2 half modules / day
 - ▶ or 6 full modules / day
- ▶ Three glueing steps:
 - ▶ glue basestrips to raw module
 - ▶ underfill sensor with glue
 - ▶ glue HDI to complete assembly
- ▶ Important: custom-made tools



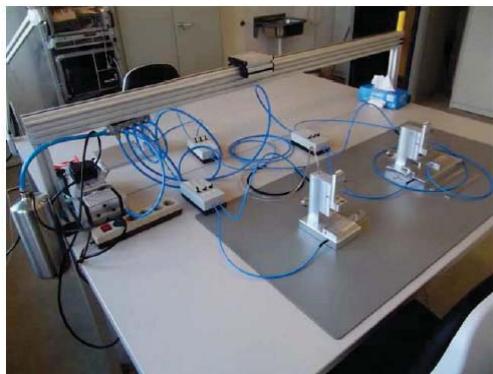
Tools and assembly line being prepared at Uni Hamburg.

D. Pitzl (DESY): CMS Pixel Upgrade

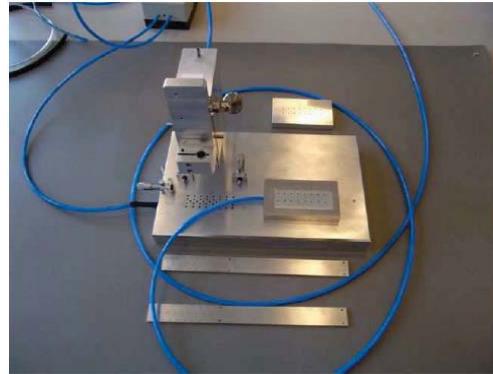
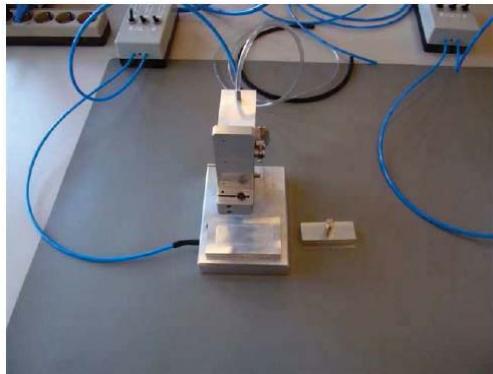
53

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Pixel module assembly tools at Uni HH



Tool rebuilt according to
PSI CAD drawings.
Gluing tests on dummy
modules underway.



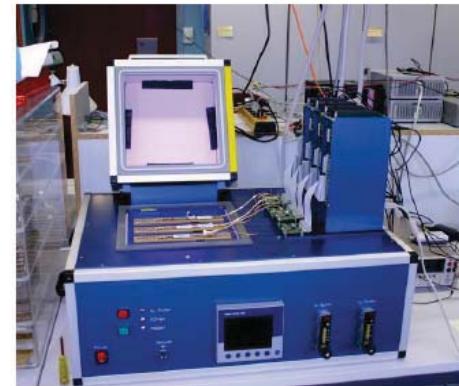
Pixel module cold calibration

► Challenges

- ▶ Huge number of channels: $5 \div 6 \times 10^7$
- ▶ Multi-dimensional parameter space: 29 DACs/ROC
- ▶ Temperature dependence: tests done at -10°C and $+17^\circ\text{C}$ **upgrade: -20°C**

► Test set up

- ▶ Programmable cooling box
- ▶ 4 modules at a time
- ▶ Custom built test-boards with FPGA

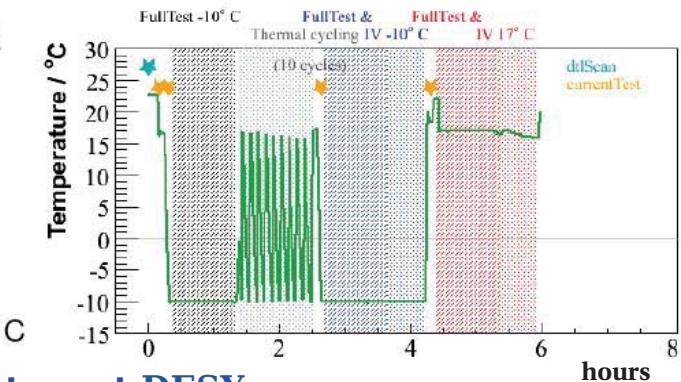


► Procedure

- ▶ Start-up adjustments
- ▶ Full Test at -10°C
- ▶ 10 thermal cycles
- ▶ Full Tests and IV at -10°C and $+17^\circ\text{C}$

Cold calibration set up will be set up at DESY.

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55

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Pixel gain calibration

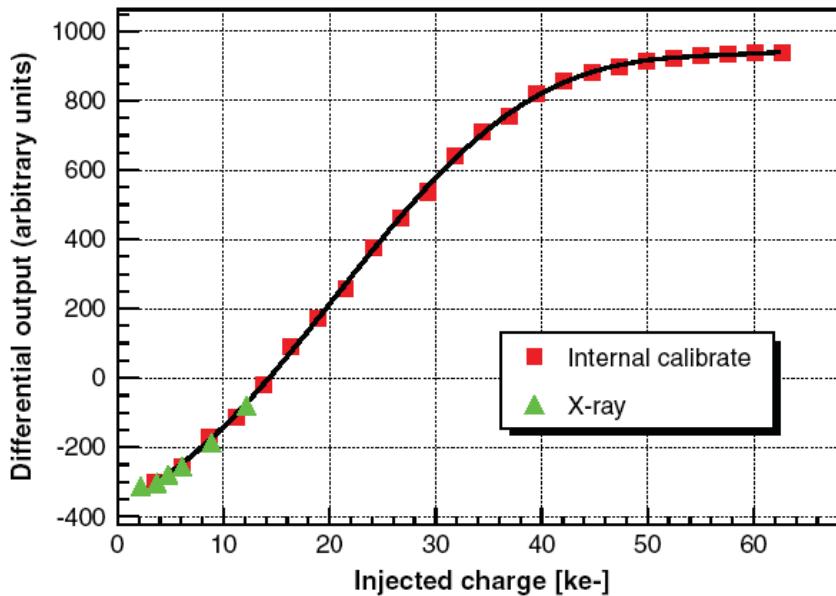
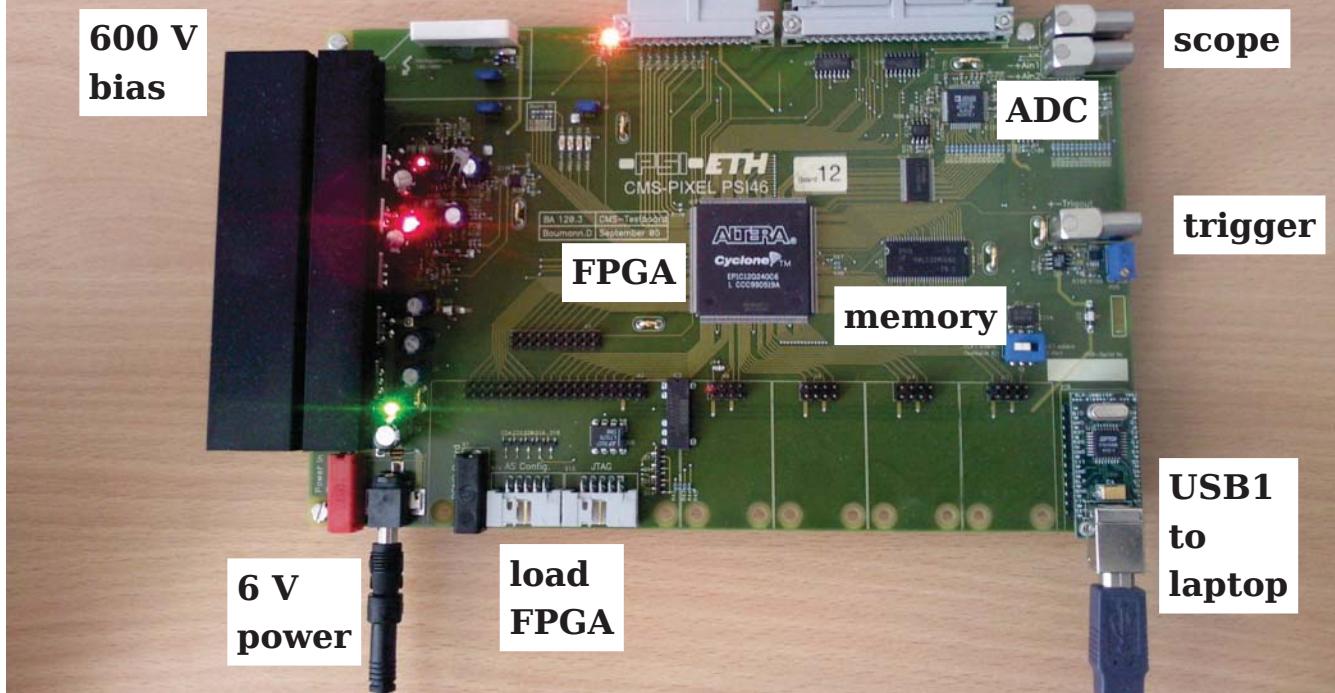


Fig. 8. Analog signal transmission.

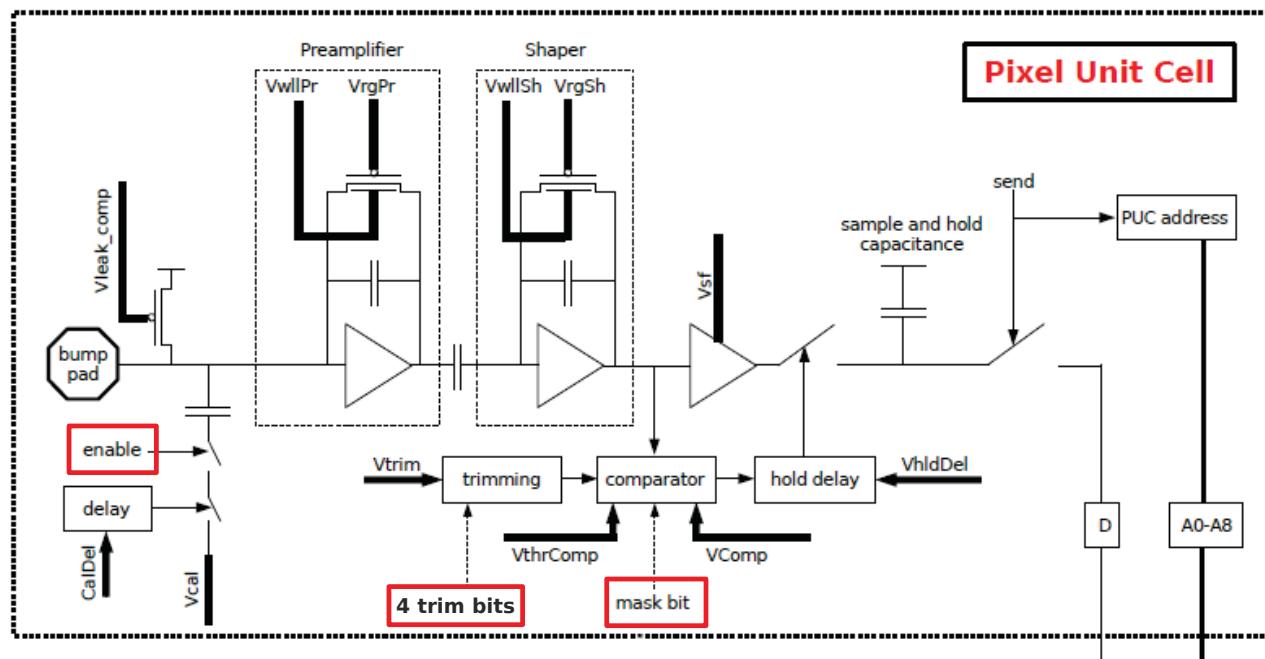
- Ultimate position resolution comes from pulse height interpolation.
- Need pixel-to-pixel gain calibration.
- Large amplitudes:
 - ▶ internal test pulse.
- Close to threshold:
 - ▶ X-ray lines (Mo, Ag, Ba).
- X-ray stand being prepared at Uni HH.

Universal pixel test board

Design and firmware
by Beat Meier, PSI



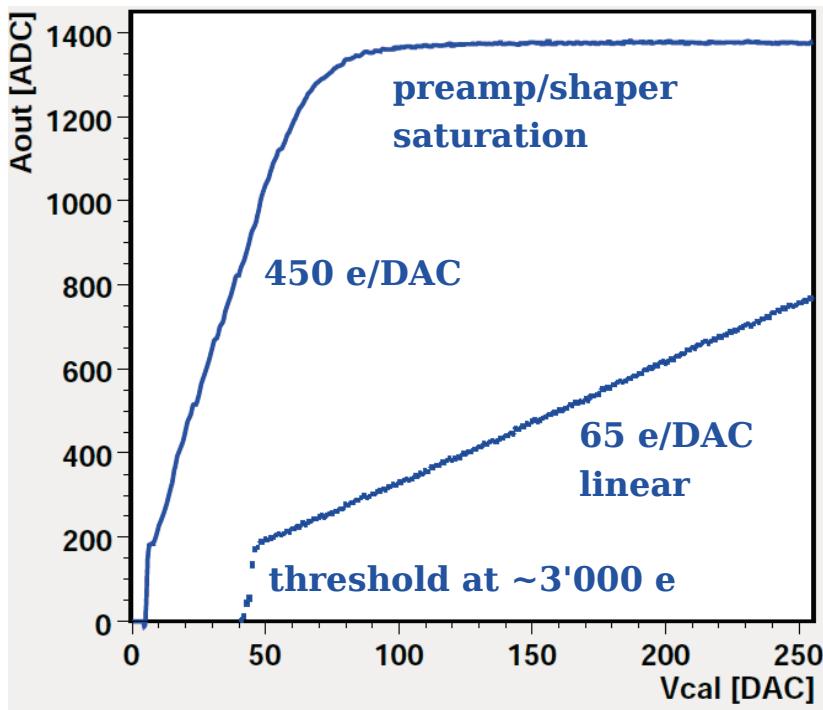
psi46 pixel readout chip



— adjustable by programmable DAC, 26 per ROC

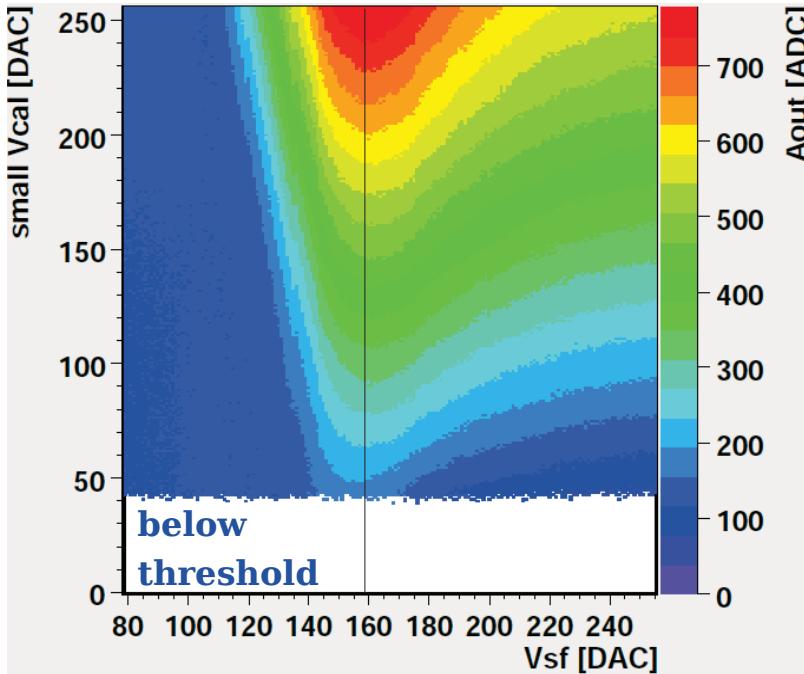
□ programmable register, 3 per pixel

gain and linear range

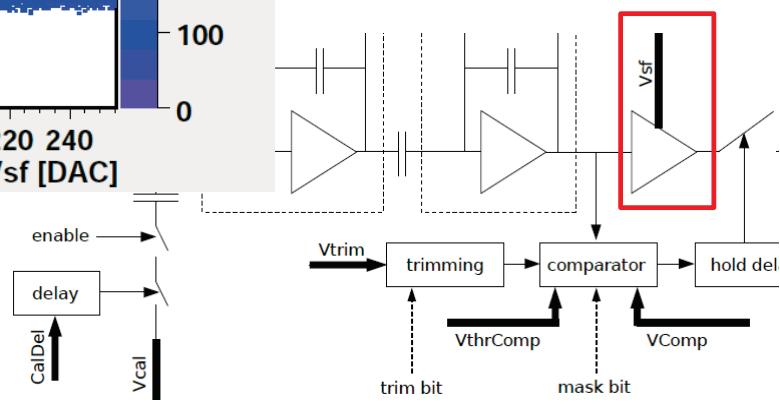


- One pixel.
- 2 V_{cal} ranges (PSI X-ray calibration):
 - CtrlReg 0 or 4,
 - 65 ± 5 e/DAC,
 - 450 e/DAC.
- Linearity for small pulses important for spatial resolution using charge sharing.
- Saturation around 36'000 e (~ 1.6 MIP).

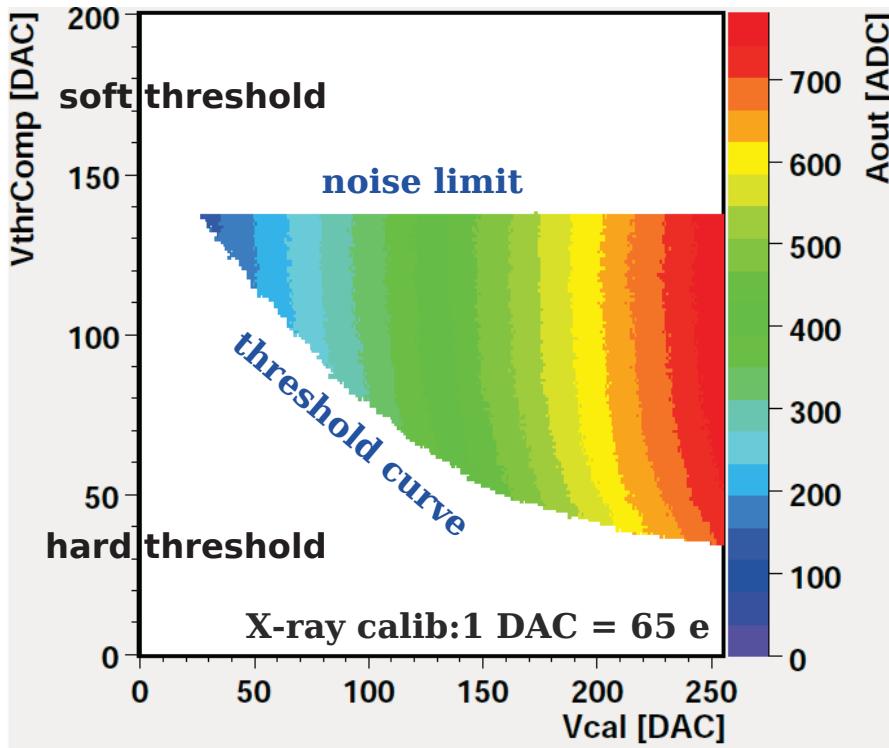
Linear range vs V_{sf}



- One pixel
- Analog pulse height vs calibrate amplitude and source follower voltage.
- Best linearity in valley.



Comparator threshold



- One pixel
- Analog pulse height vs threshold and calibrate amplitude.
- White region:
 - no signal.
- Colored bands are not vertical:
 - time walk.

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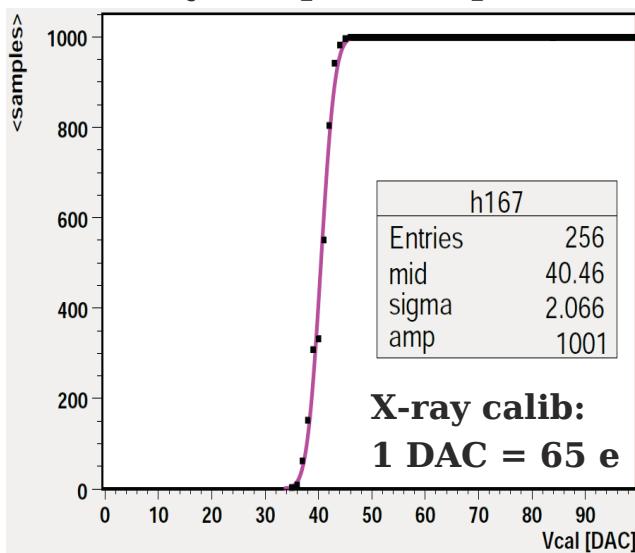
61

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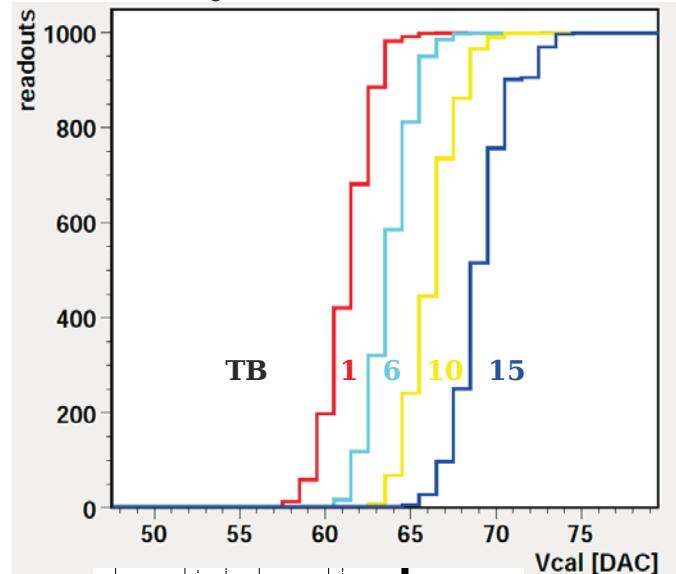
Threshold curve

one pixel

vary test pulse amplitude



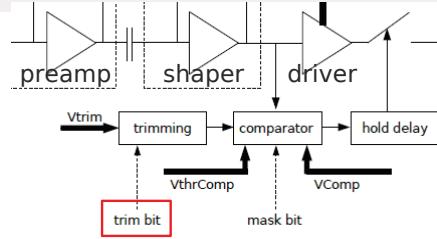
vary trim bits



threshold broadened by noise

fit by error function

noise: 130 e



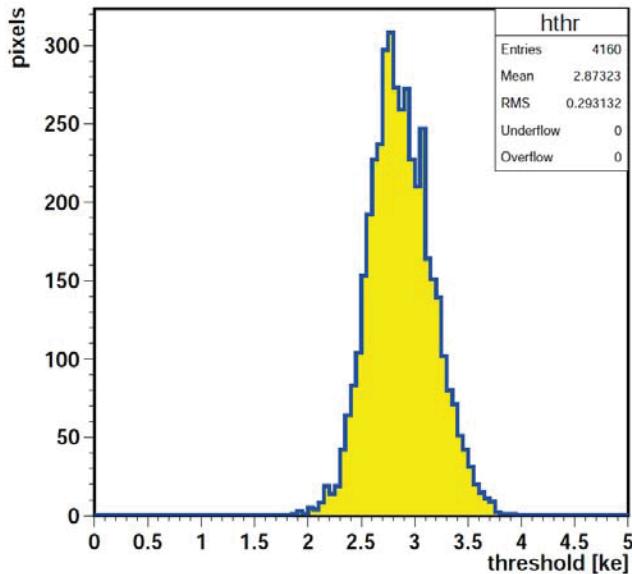
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62

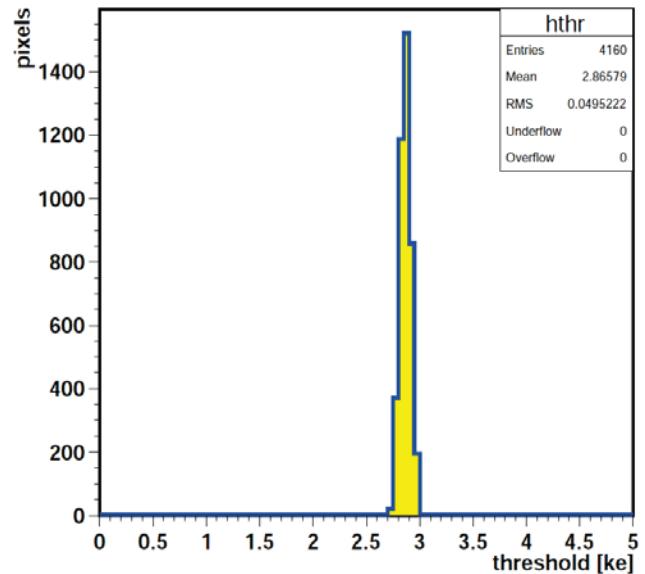
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Threshold variation

4160 pixels / chip



the same chip, trimmed:



**CMS transistor variations:
threshold spread 290 e**

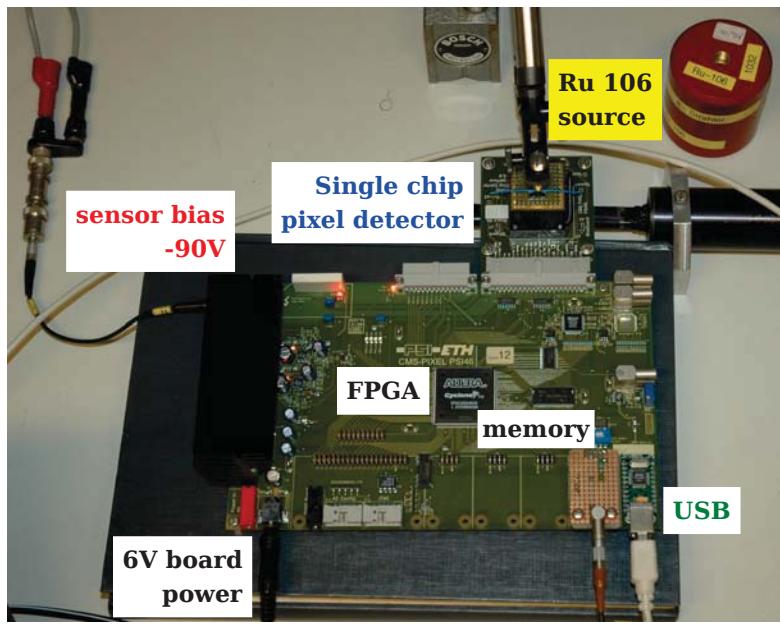
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63

**4-bit DAC trimming:
threshold spread 50 e**

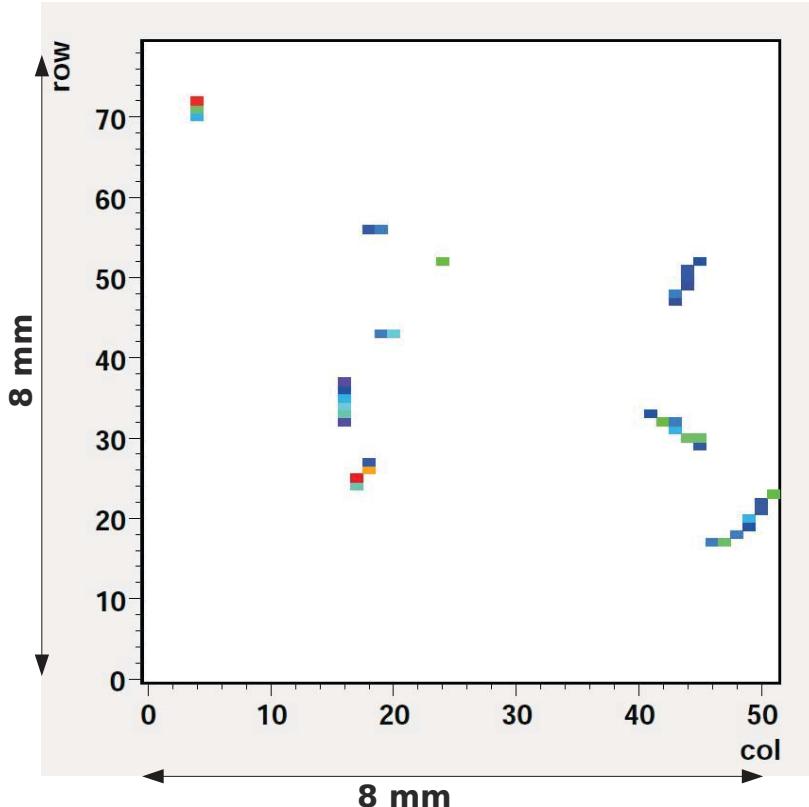
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Source test setup



- ^{106}Ru source mounted above the chip:
 - Activity ~ 14 kHz,
 - electrons up to 3.5 MeV.
- FPGA:
 - data clock cycle stretched up to 1 ms,
 - trigger,
 - readout,
 - store in memory.
- Final readout by USB.

Source test event display



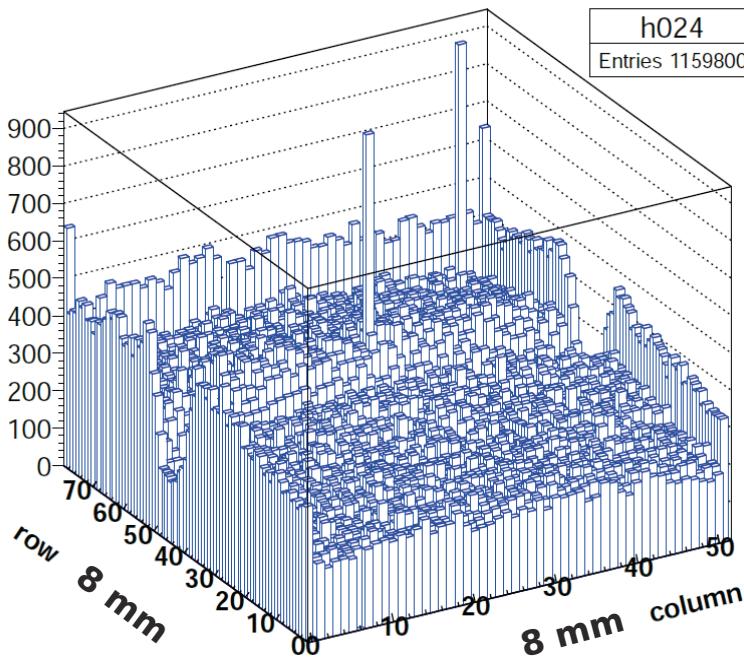
- A single event integrating over 1 ms:
 - ▶ ~15 hits per trigger
- Low energy electrons:
 - ▶ Scattering in the source holder,
 - ▶ wide angles of incidence,
 - ▶ large clusters.
 - ▶ tracks visible.
- Clusters of pixels identified by software.

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65

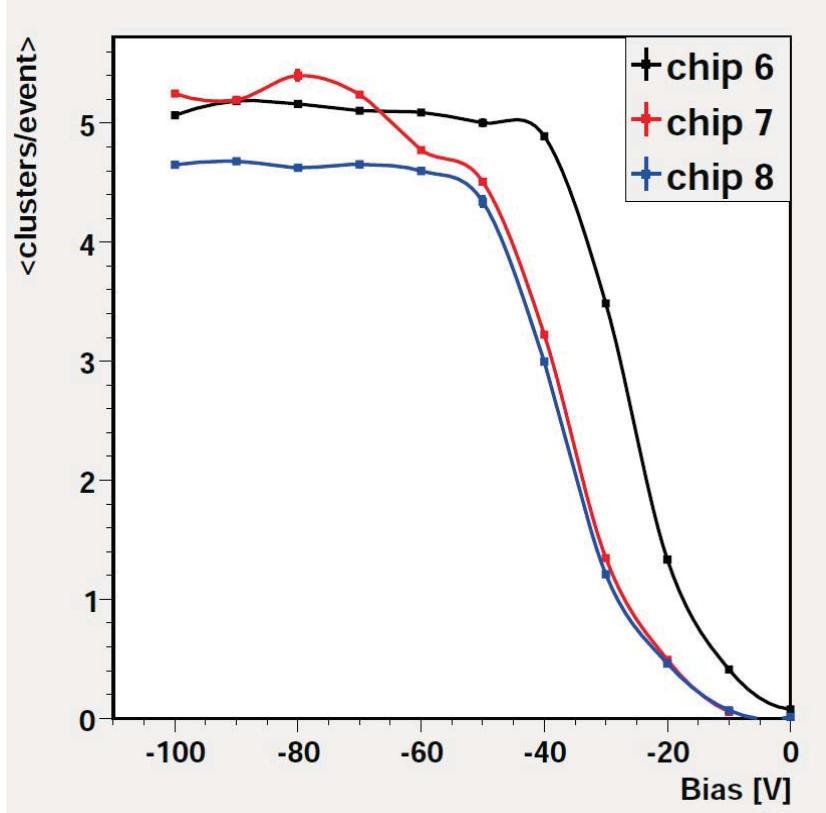
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hit map



- Ru source, 100s.
- Wire placed across the chip.
- Pixel map (φ - z):
 - ▶ shadow of the wire
 - ▶ 2 noisy pixels.
 - ▶ long and/or wide pixels at 3 edges.

Cluster multiplicity vs. bias voltage



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67

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- Ru106 source.
- All scans with:
 - Internal trigger
 - Clock stretch 1 ms
 - 10s run for one Vbias value
- Cluster efficiency saturates below -50 V.
- Plateau variation:
 - Source position,
 - Thresholds.

DESY II

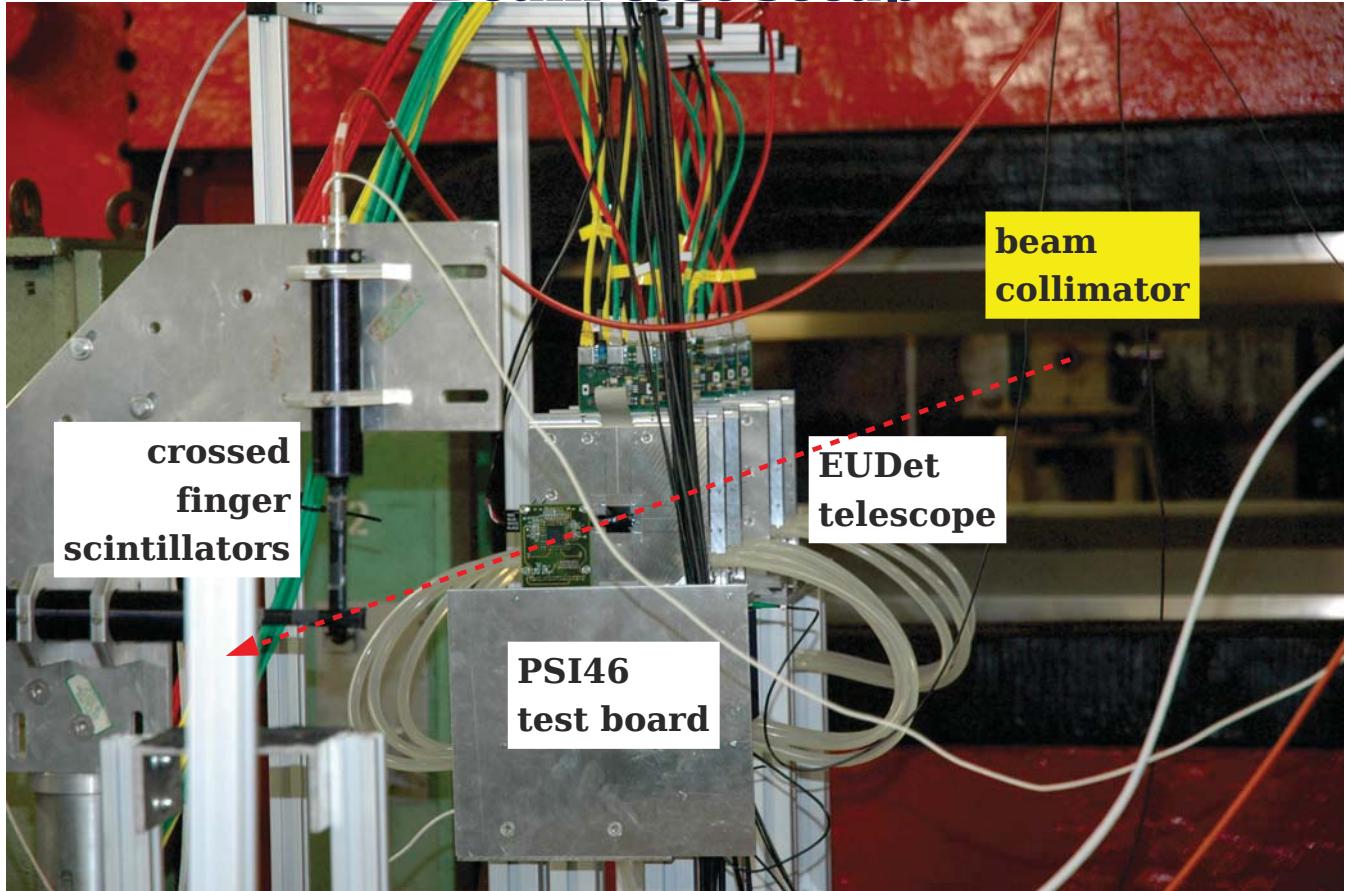


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68

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Beam test setup

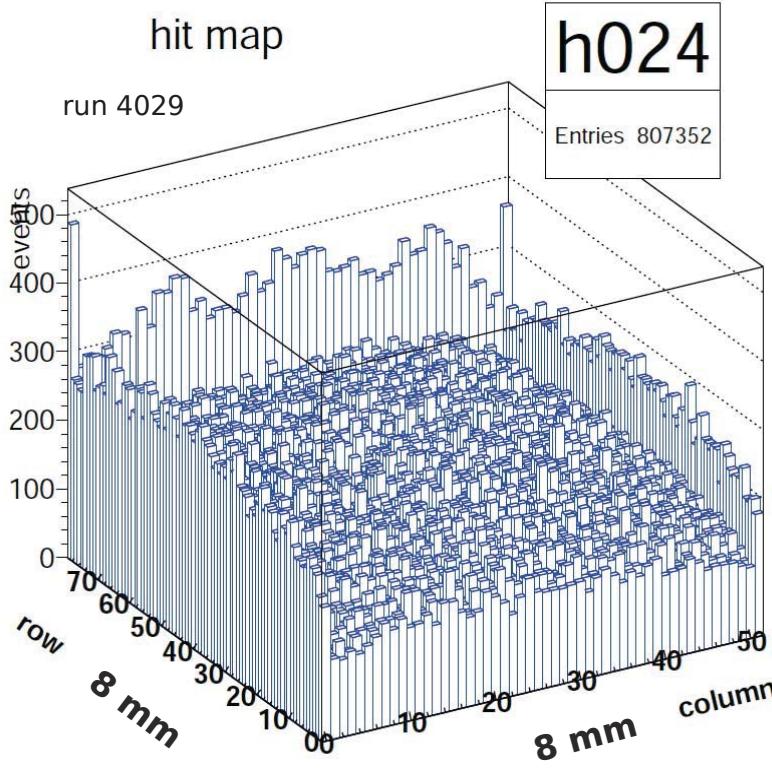


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69

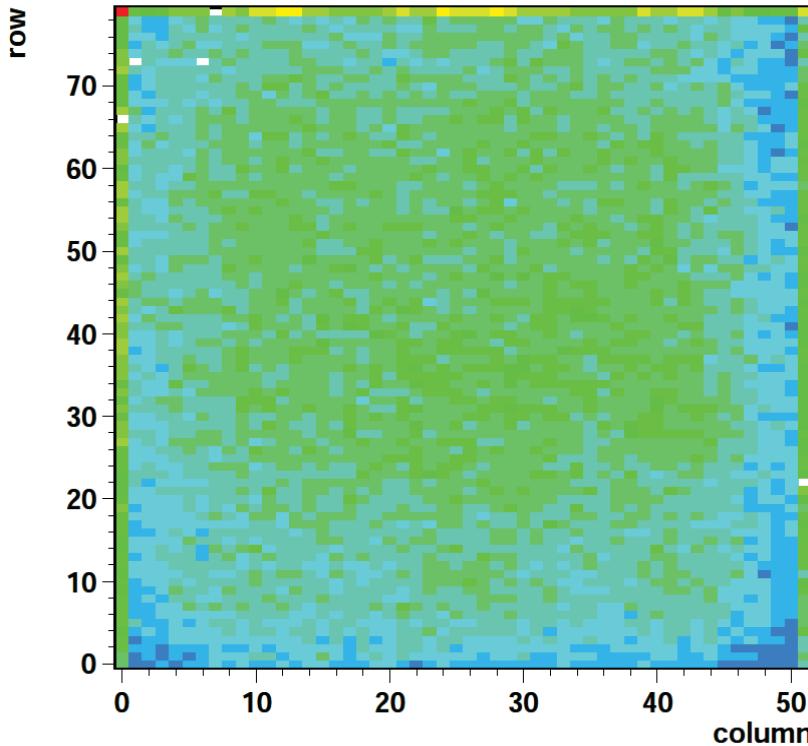
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Pixel hit map



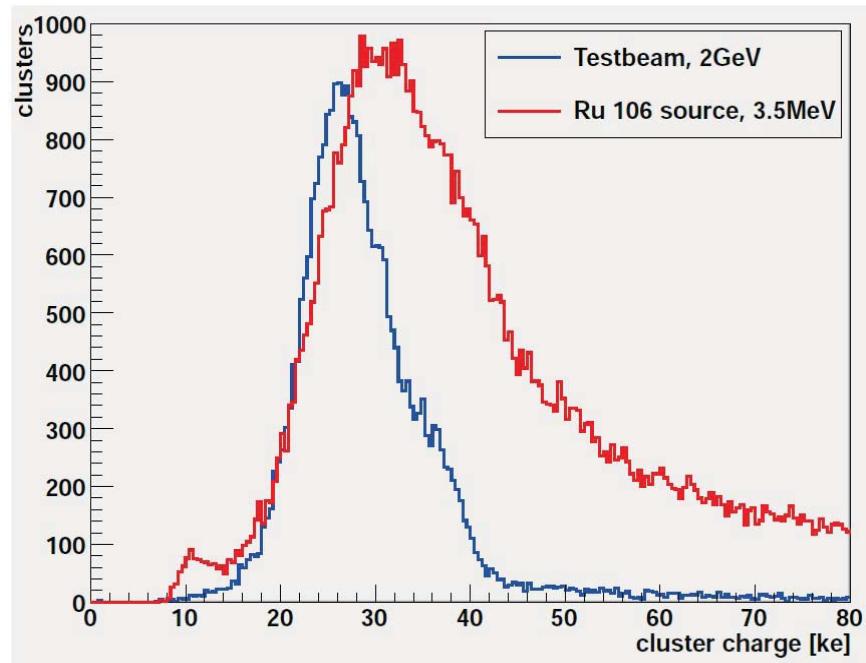
- 2 GeV e^+ beam.
- After space and time alignment:
 - ▶ 4 kHz coincidence rate
 - ▶ Fill test board memory: 60MB in 3.5 min.
 - ▶ USB transfer takes another \sim 2 min.
- One chip fully illuminated.
- Border pixels have double size and rate
- Corner pixels have quadruple size and rate

Pixel hit map



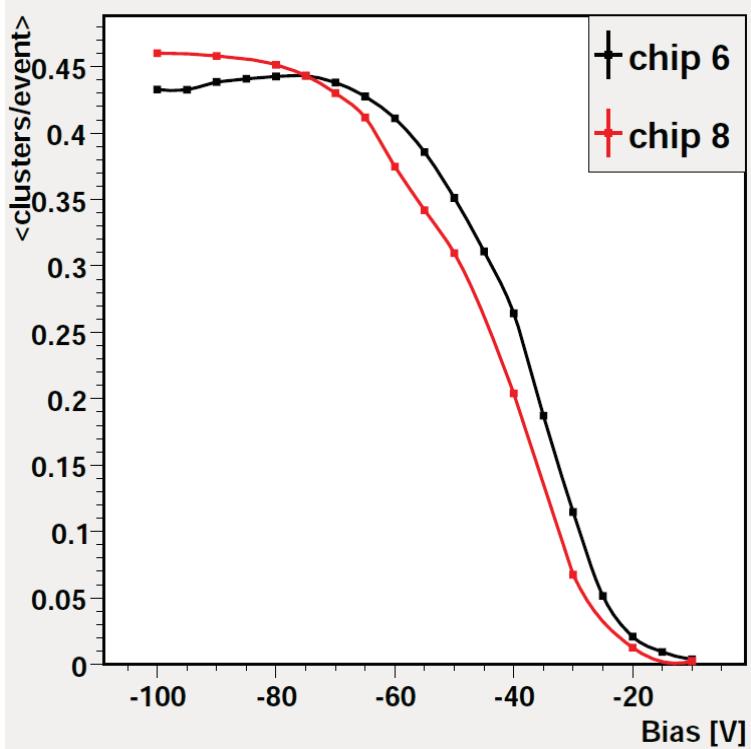
- the same run
- a few dead pixels
- non-uniformity:
 - ▶ beam profile,
 - ▶ misalignment between sensor and scintillator,
 - ▶ limited trigger region ($\sim 1 \text{ cm}^2$) just enough to cover $0.8 \times 0.8 \text{ cm}^2$ chip.

Cluster charge: Ru source vs beam



- Chip 8, -90V bias, Vthr 100
- 2 GeV e+ test beam:
 - ▶ Minimum ionizing particles
- Ru 106 source:
 - ▶ long tail of stronger ionizing electrons (not fully relativistic).

Cluster mult[ilc] vs bias voltage



- 2 GeV e⁺ beam.
- Cluster efficiency saturates below -80 V:
 - ▶ Need more bias voltage to reach full efficiency for minimum ionizing particles.

Project time line

- Produce assembly tools since 2010
- Develop assembly procedures 2011
- Develop testing and calibration procedures 2011
- Bump bonding tests 2010-2011
- Decide on bump bonding technique end 2011
- Contribute to R&C pre-series testing 2012
- Assembly and test procedures established 2012-2013
- Receive all components for series production 2013-2014
- Module assembly and calibration 2013-2014
- 1st layer assembly and test end 2014
- Full system test at CERN 2016
- Ready for installation in CMS end 2016

□ or □ packages □ □ C□ □

□th la□er: □□□ mo□ules □ □□ s□ares □ □□ re□ects □ □□

task	quantity	DESY	HH	Ka	Ac
sensors I-V	700		350	350	
bare module test	700	350		350	
bond TBM to HDI	700	350		350	
glue HDI to sensor	700		350	350	
bond ROCs to HDI	400k	200k		200k	
module testing	700	350		350	
cold calibration	700	350			350
X-ray calibration	700		350		350
layer assembly	1	1			
layer system test	1	1			
DC-DC converters	2200				all

□ eo□le at □ □□ a□□ □ □□ amburg □□□

- DESY:
 - G□nter Ec□erlin, deputy CMS group leader, DPix coordinator
 - Daniel Pitzl, pixel upgrade project leader
 - Carsten □ iebuhr, Doris Ec□stein, staff
 - Maria □ ldaya, □an □ lzem, □lexey Petru□hin, □ anno Perrey, postdocs
 - □arsten □ ansen, □an □ ampe, staff □EC
 - Carsten Muhl, □ olger Maser, engineering
- Uni □ amburg:
 - Peter Schleper, professor
 - Georg Steinbr□c□, staff
 - Thomas □ ermanns, postdoc
 - □utz □ erger, technical support



Summary

- The present CMS pixel detector is working very well and is an essential tool for track reconstruction and vertexing.
- The LHC luminosity is expected to exceed $10^{34} \text{ cm}^{-2}\text{s}$ in this decade:
 - ▶ the present pixel readout chip will become inefficient.
 - ▶ at least the inner pixel layer has to be exchanged after 200 fb^{-1} .
- A -layer replacement with a new readout chip has further benefits:
 - ▶ better resolution, efficiency, and purity for pixel-based tracking,
 - ▶ Reduced material in the tracker volume with C_2O_2 cooling, low mass design, services moved out of the tracking region.
- The German CMS institutes have been asked to contribute:
 - ▶ Design optimization and physics evaluation,
 - ▶ module assembly and testing,
 - ▶ DC-DC converter development and production.
- Preparations are underway.

CMS summer tests

- Alexander Abos
 - summer student from Cracow
- Boris Balakov
 - summer inter
- Beat Eder Thomas Eder Ulrich Rohe:
 - for code advice
- Irich Koett
 - for lab space to create modules oscilloscope
- Laumr a
 - for the source
- Carsten Uhl
 - for the source holder
- Norstet Eller
 - for the VME trigger alter
- Christian Grigorov test beam coordinator:
 - for structural parts a test beam hospital
- Robert Eilers
 - for help with collimator a fire target
- Samuel Hararajal
 - for help with moving system a rate monitor
- Holger Kaser
 - for the test board support frame
- Priska Arutunian
 - for the trigger scintillator a monitor
- Michael Achleitner
 - for the steady test beam

vacuum sleeves

PRC-2010-69-3

The CMS Tracker upgrade

– DESY contributions –

April 15, 2010

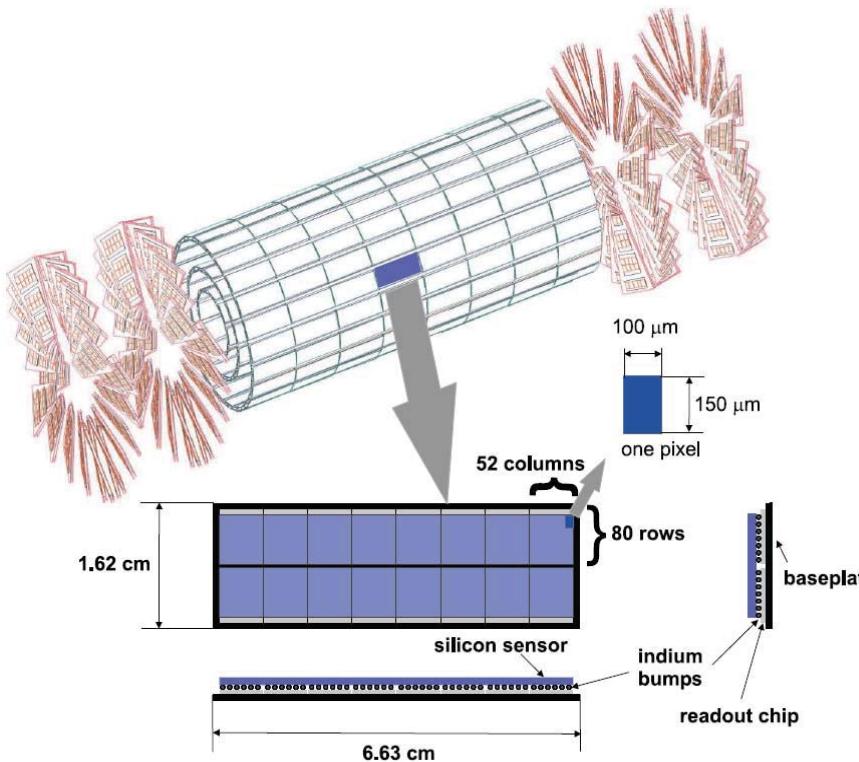
The DESY CMS Group

Abstract

A 4-layer low mass replacement of the CMS Barrel Pixel detector is planned for the middle of the decade. DESY is interested to contribute to the module production, in collaboration with the universities in Hamburg, Karlsruhe and Aachen. At a later stage, the entire silicon tracker needs replacement to cope at higher luminosity with increased track density and larger radiation dose while the material budget should be reduced. DESY R&D activities within the Central European Consortium involving the above mentioned universities and those in Barcelona, Louvain and Vilnius are described.

- DESY PRC document for the CMS Tracker upgrade.
- Pixel and Strips
- Hamburg and Zeuthen
- Submitted April 2010.
- Positive recommendation.

CMS Pixel



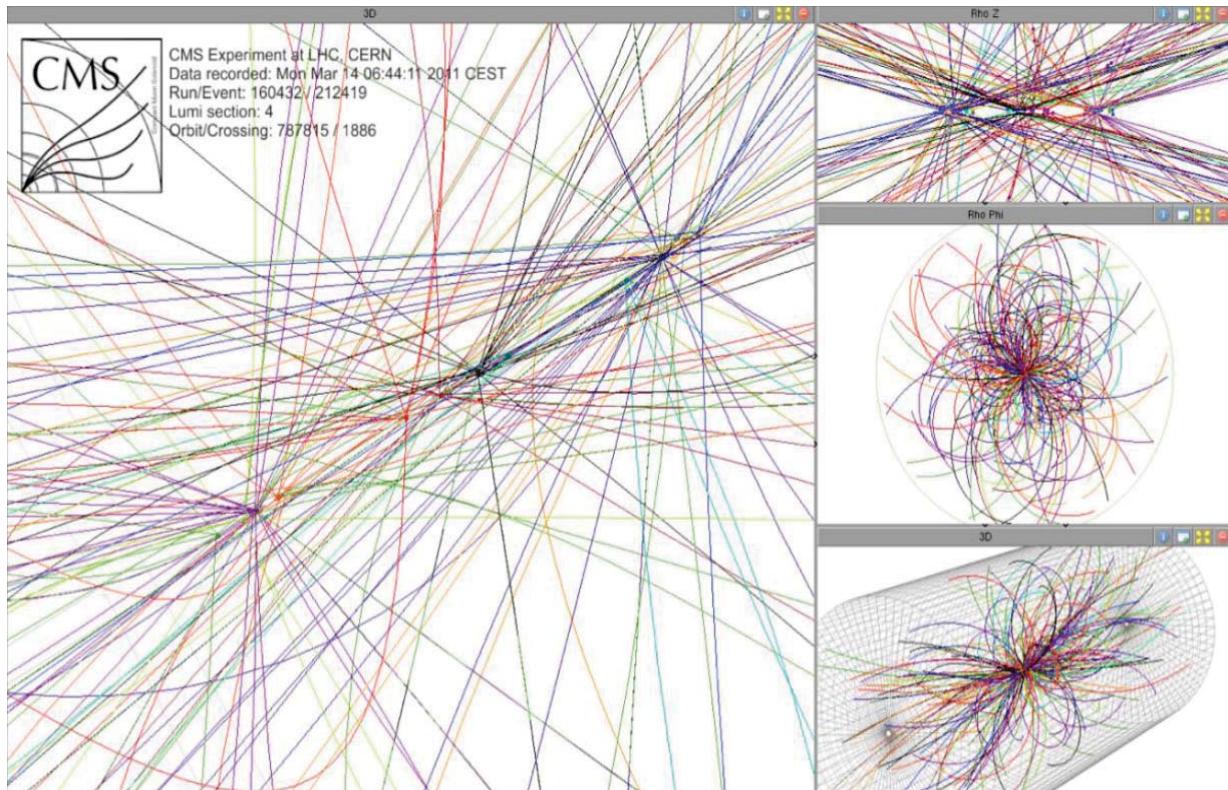
D. Dorošov
Uni Zurich
200□

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81

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3D Data

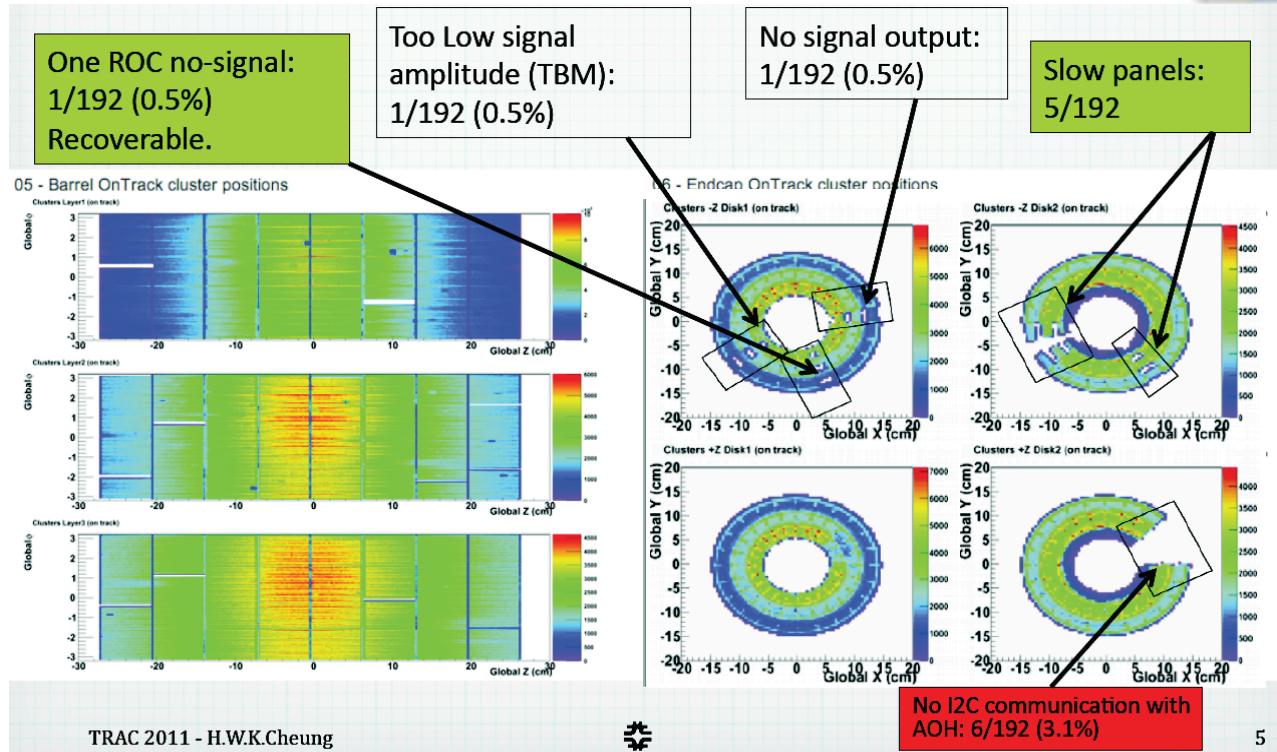


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82

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Pixel operation



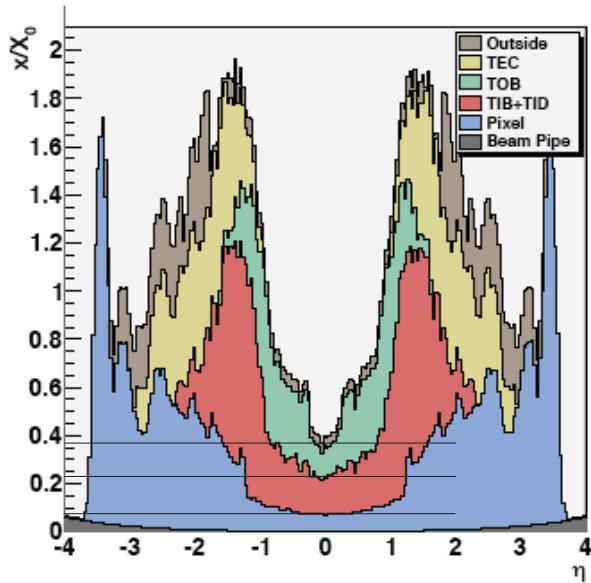
D. Pitzl (DESY): CMS Pixel Upgrade

8

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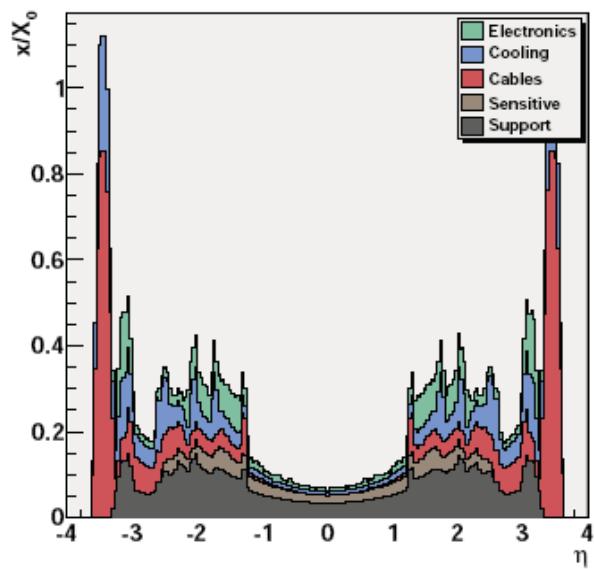
C_ontracted material

All trackers



pixel note 2009

Barrel pixel



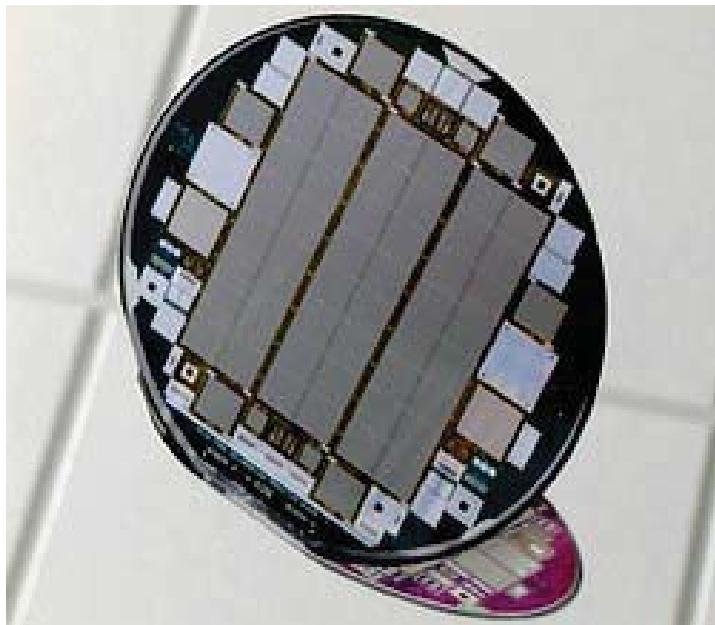
Upgrade:
factor 2 less in center
factor 4 less in endcaps

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CMS Pixel Sensors



design: Tilman Rohe, PSU

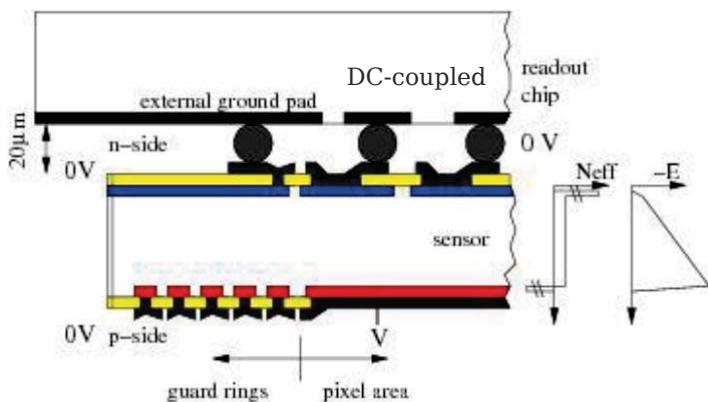
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80

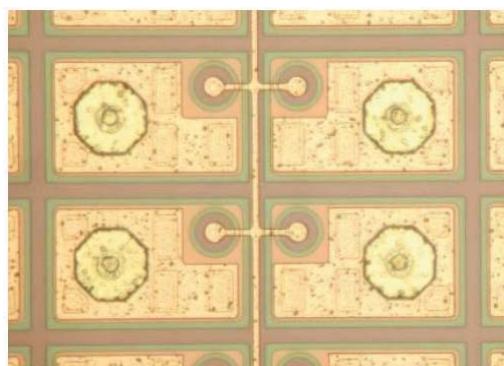
- 60 wafers under production at CMS (Erfurt)
 - standard CMS pixel sensor design (double sided, n-in-n, p-spray insulation).
 - for Karlsruhe, INFN, CERN Taiwan, MRU, Purdue, DESY.
 - 10 wafers with increased bump pad passivation opening: 100 µm, for DESY.
 - Delivery in Feb 2012.
- Null sensors for first bump bondings.
- Single chip sensors for tests with new ROCs.

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Pixel sensors

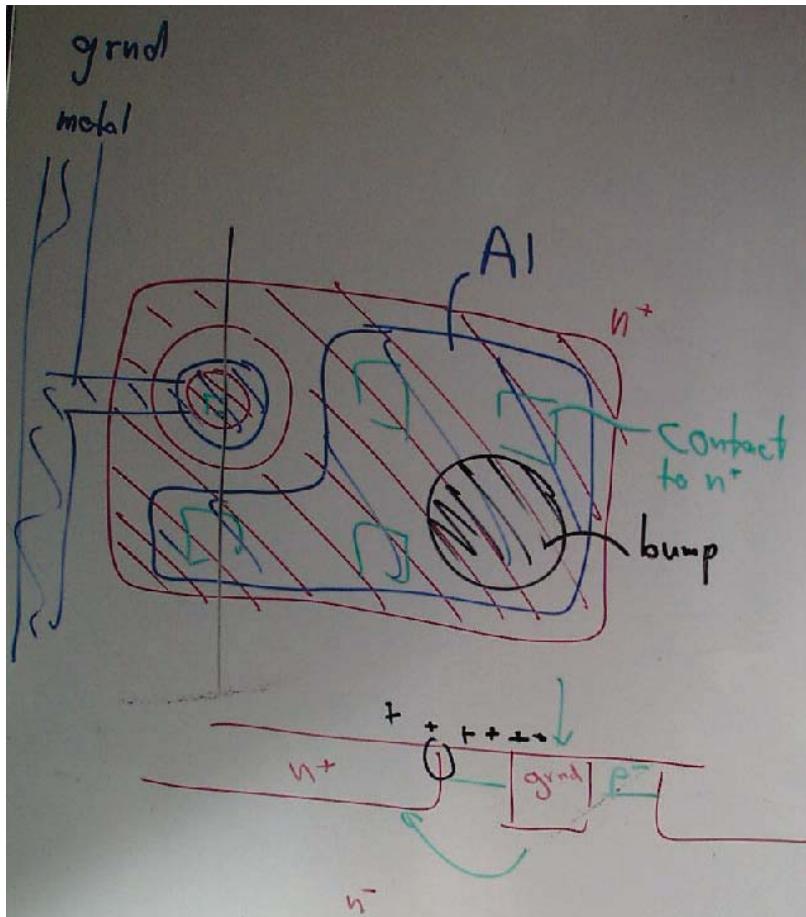


- Planar sensors, CiS Erfurt.
- 111-oxygenated float zone.
- n-in-n, p-spray insulation.
- collecting faster electrons:
 - larger Lorentz angle,
 - less trapping.
- pn-junction on back side (initially):
 - edges at ground,
 - double sided processing.



100 m m m m m m m m

Grounding grid for testing before bump bonding



□ □ □ el

Rohe
c g

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87

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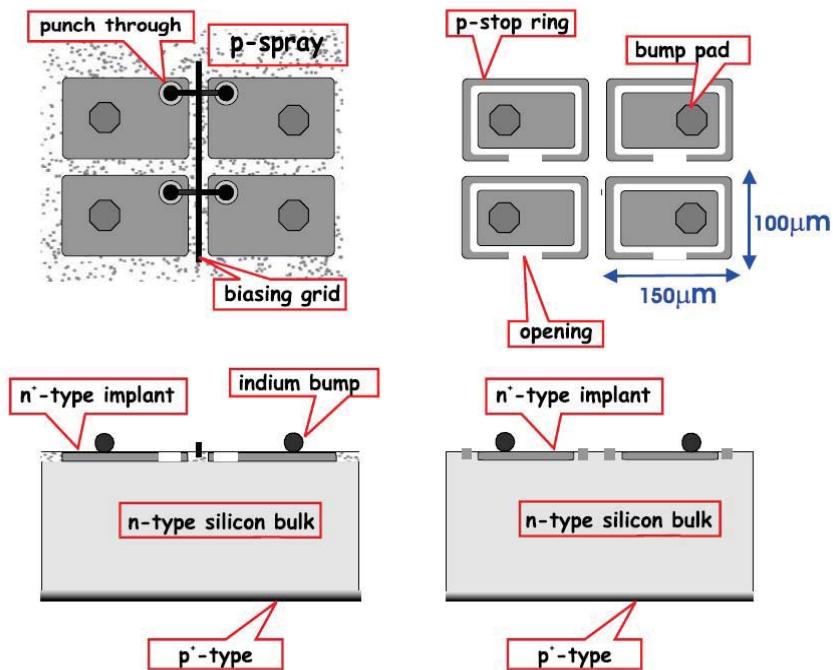


Figure 1.11. Sensor designs for the CMS barrel detector (left) and end-caps (right).

□. Doro□hov
Uni Zurich
200□

CMS barrel pixel sensor design

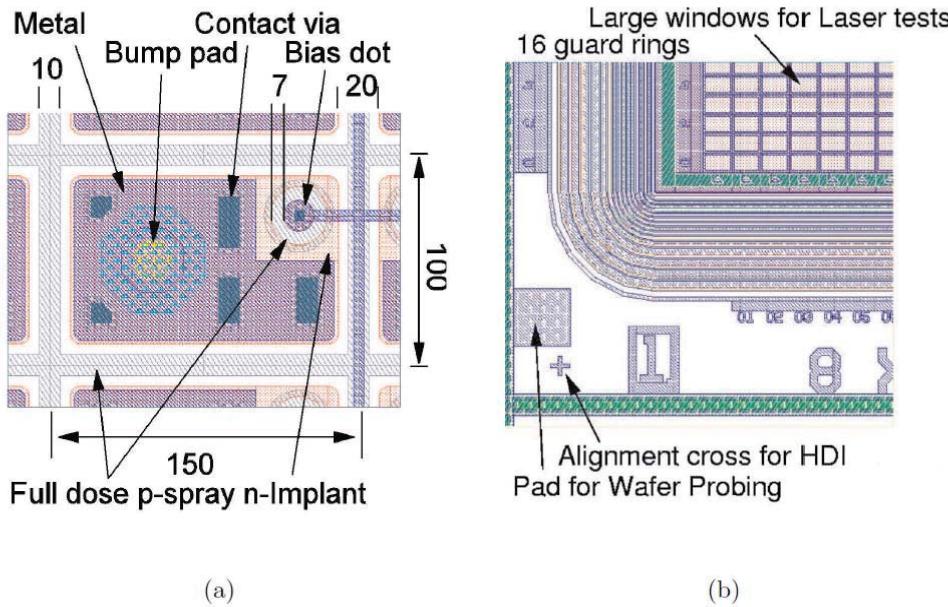


Figure 1.12. The masks for the p-spray design. Left: The mask layout of the pixel side. The distances are in μm . Right: The mask layout of the backside.

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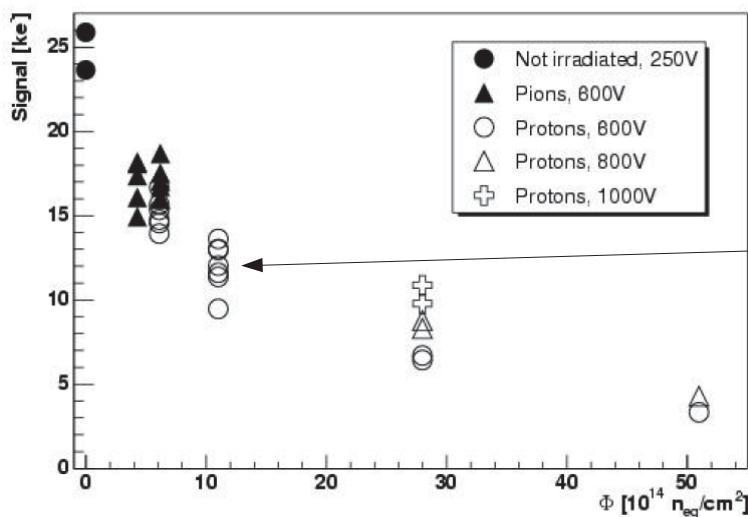
T. Rohe (PSD), from J. Dorofov (Uni Zurich) 2000

89

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Detector radiation damage

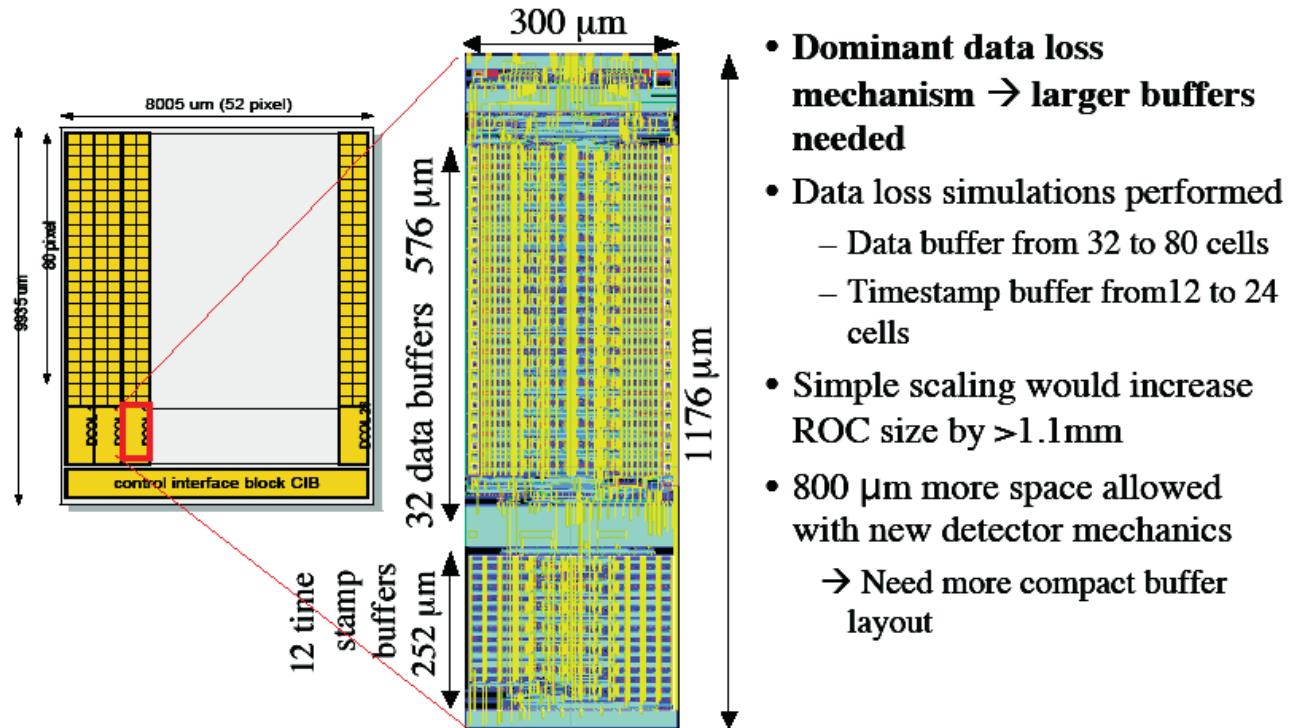
Global collection in CMS barrel sensors



© Rohe et al. 2000

- Inner barrel layer:
 - $70 \text{ fb}^{-1} \approx 10^{10} \text{ n/cm}^2$
 - $200 \text{ fb}^{-1} \approx 10^{11} \text{ n/cm}^2$
- ~10% signal loss after 200 fb^{-1} .
- Also leads to factor 2 degradation of the hit resolution (less charge sharing and Lorentz angle).
- Bias voltages above 600 V not possible with the present CMS HV system.
- MCz being considered.

Large on-chip buffer



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91

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Large on-chip buffer

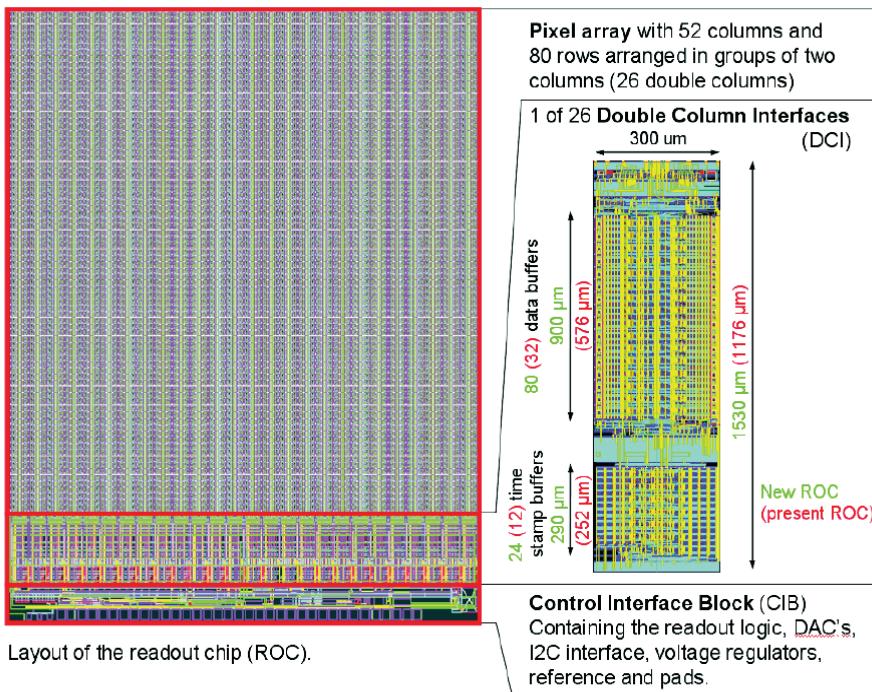


Figure 1. Layout of the existing readout chip (ROC). A detailed view of the double column interface with size of the new chip compared to the old one.

D. Meier (PS)
ov 2010
JINST 6 C01011

Karlsruhe aachen

- Karlsruhe:

- Ulrich Gusemann, Thomas Müller, professors
- Marc Eber, professor, director LPE
- Thomas Ganzenmüller, staff LVT
- Michele Caselle, Alexander Dierlamm, Christian Hartmann, Thomas Eiler, staff
- Stefan Eindl, phd student
- Tobias Garvich, technical support



- Aachen:

- Ulfeld, professor
- Katja Lein, staff
- Jan Sammet, phd student
- technical support



ateleria

- Roland Grisberger, Wolfram Erdmann, Hans-Christian Göstli, Tilman Rohe, Beat Meier, Silvan Streuli, Illi Hörtl, Urs Langenegger, Daniel Orlinschi
- Rainer Hallny, Andrei Starodumov
- Peter Robmann

